

Diagnostic techniques for cultural heritage: applications of synchrotron infrared spectroscopy to the study of a painting cross sections



Mariangela Cestelli Guidi
Sinbad IR beamline @ DaΦne

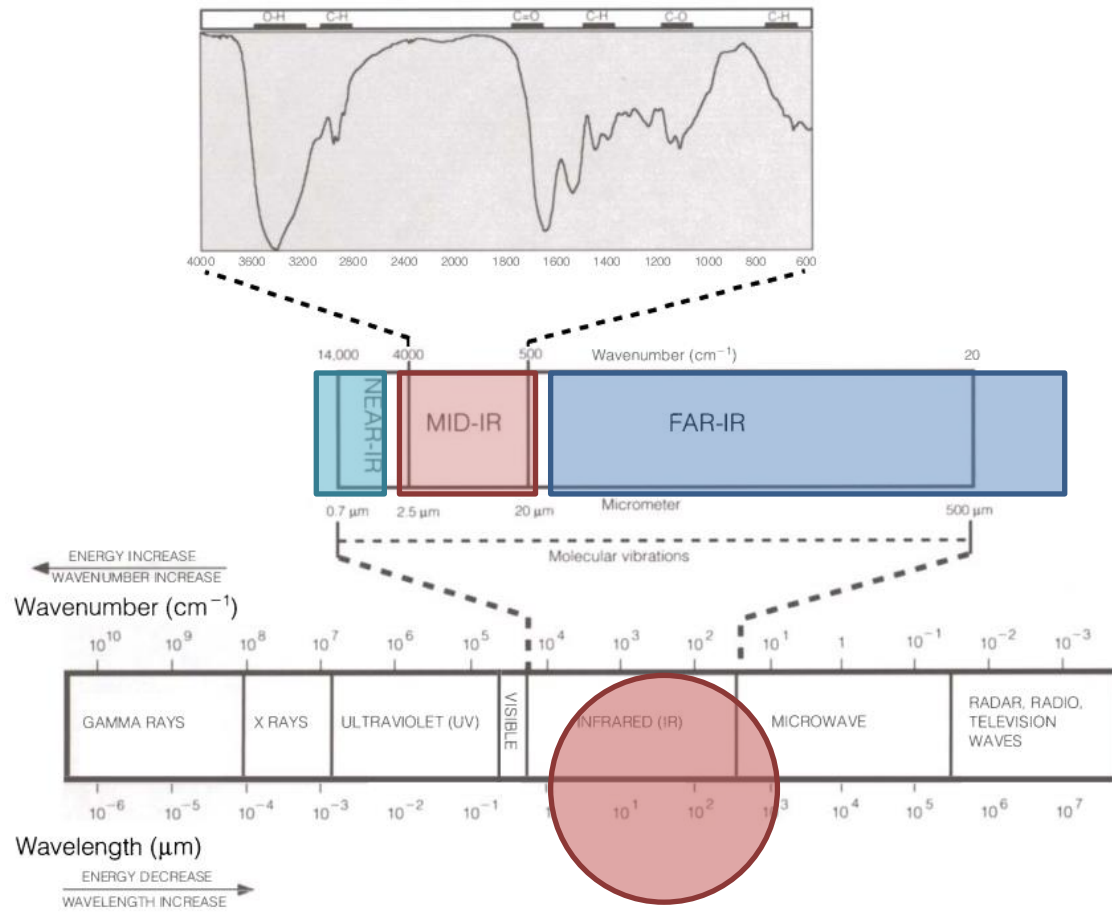
INFN-International Masterclass 2014

Layout

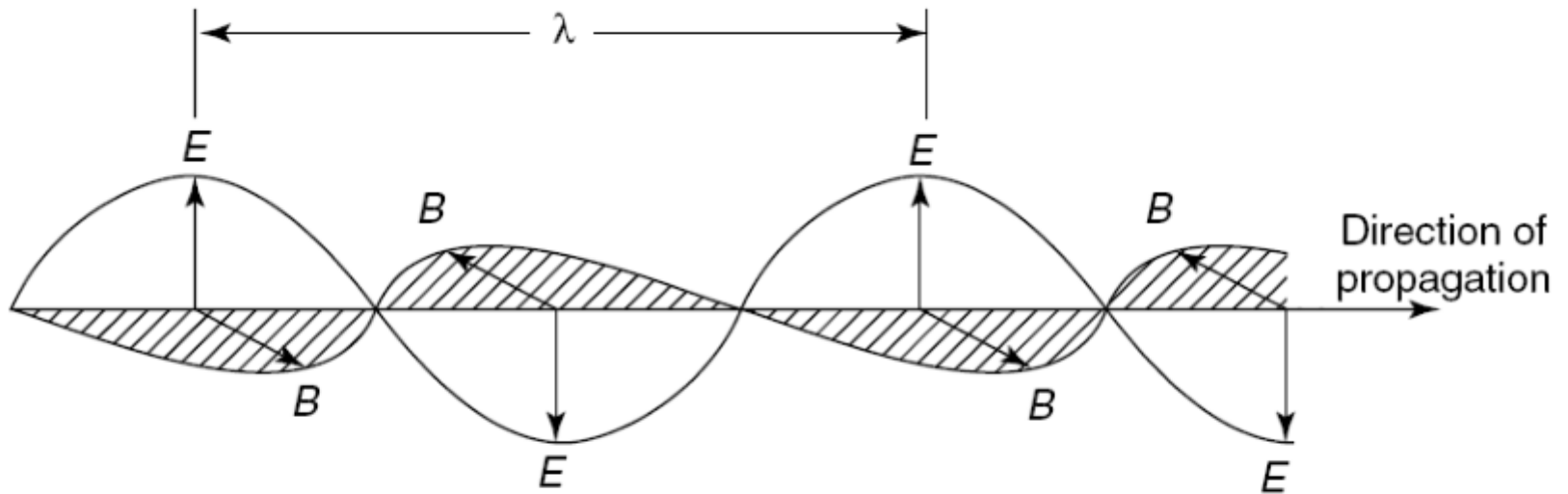
- FT-IR spectroscopy in cultural heritage
- Sampling techniques: transmission, reflection, Attenuated total reflection (ATR) and Diffuse reflection (DRIFT)
- Infrared imaging and microscopy: generating chemical images from a sample
- FT-IR Analysis of a painting cross section

FOURIER TRANSFORM INFRARED
SPECTROSCOPY (FT-IR):
physical principles

Electromagnetic spectrum and IR



The EM field

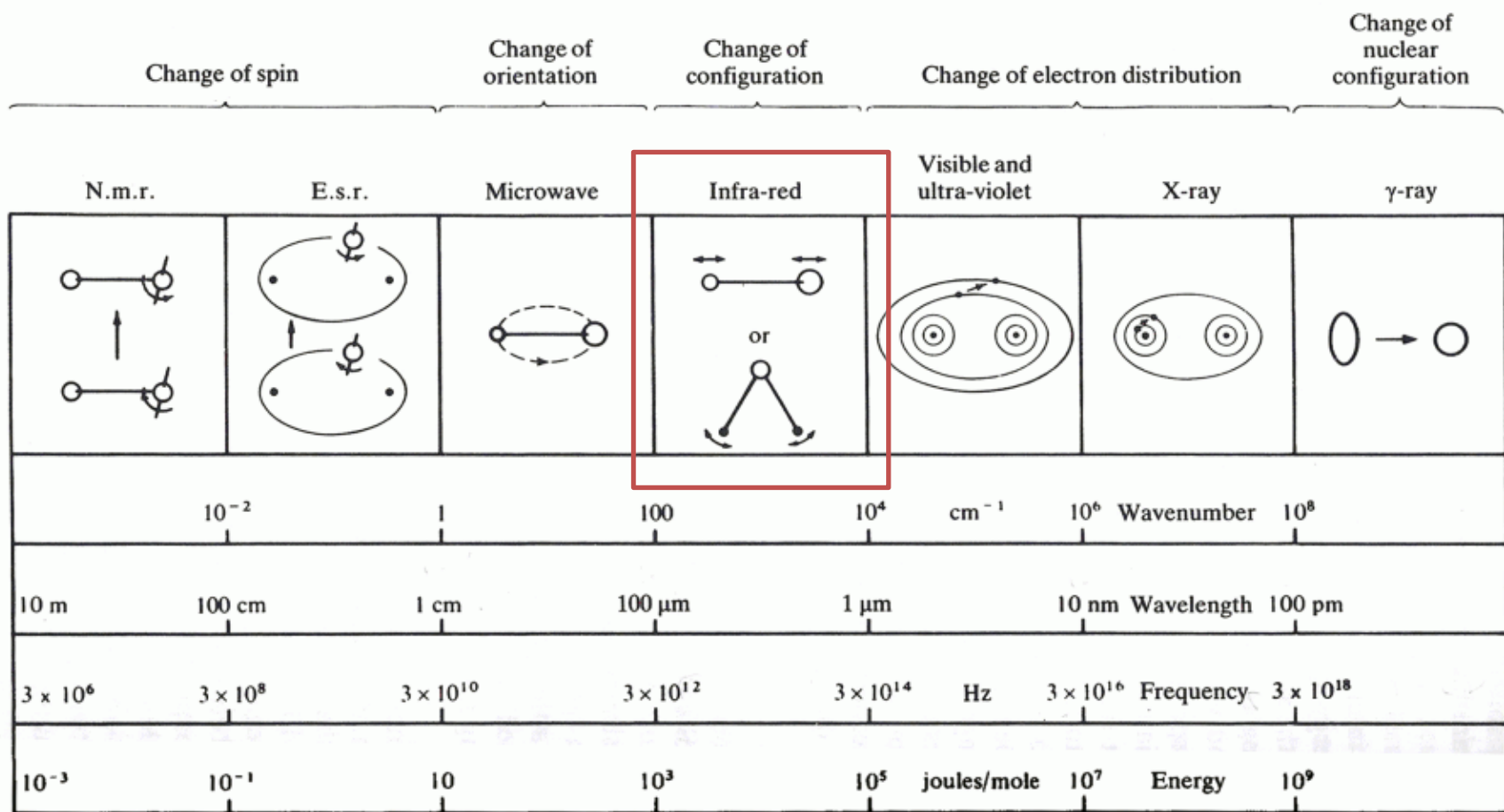


IR Units

- Visible and IR light are both EM radiation, differing only for the wavelegth. They both propagate in vacuum at the light speed c .
 - Wavelength λ (μm)
 - Frequency ν (**Hz**: $\nu=c/\lambda$)
 - Energy E (**eV**: $E=h\nu$)
 - Wavenumber $\tilde{\nu}$ (**cm^{-1}**)

$$\tilde{\nu} (\text{cm}^{-1}) = 1/\lambda (\text{cm})$$

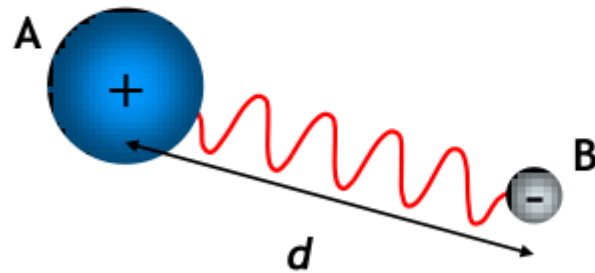
What happens when «light» interacts with matter



$$E_{\text{total}} = E_{\text{translational}} + E_{\text{rotational}} + E_{\text{vibrational}}$$

Every molecule interacts with the IR EM field?

- There is an interaction if there is a variation of the electric dipole moment:



$$\mu = |\delta e| \cdot d$$

IR active modes

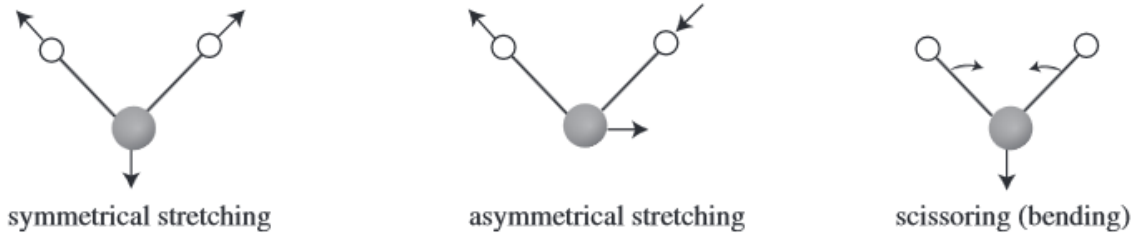


Figure : Stretching and bending vibrational modes for H₂O

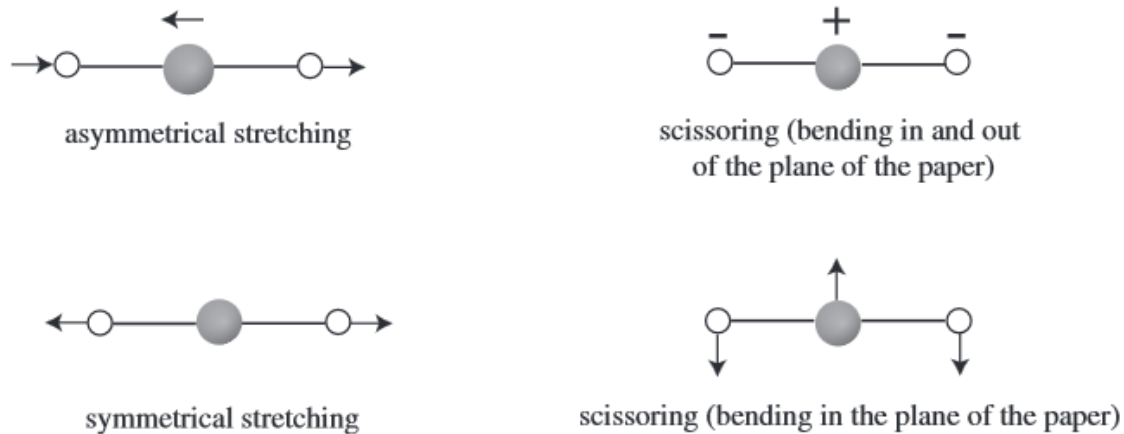
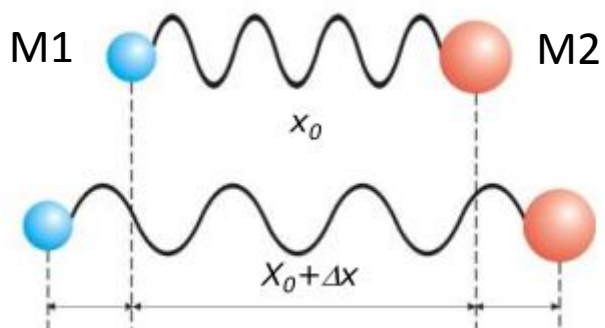


Figure : Stretching and bending vibrational modes for CO₂

- O₂, H₂, Cl₂, N₂ are not IR active!



$$\nu = \sqrt{\frac{k}{m}} \text{ vibration frequency}$$

$$m = \frac{M1 \cdot M2}{M1 + M2} \text{ (reduced mass)}$$

Increasing k (bond strength) the frequency increases
 Decreasing m , the frequency increases.

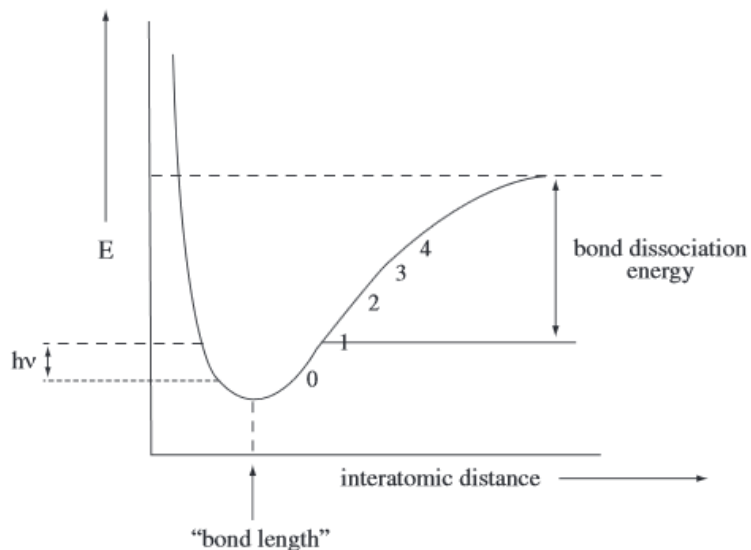
C-C, C-O, C-N \rightarrow 800-1300 cm^{-1}

C=C, C=O, C=N \rightarrow 1700 – 1900 cm^{-1}

C \equiv C, C \equiv O, C \equiv N \rightarrow 2000-2300 cm^{-1}

C-H, N-H, O-H \rightarrow 2700-3800 cm^{-1}

Modi normali di vibrazione



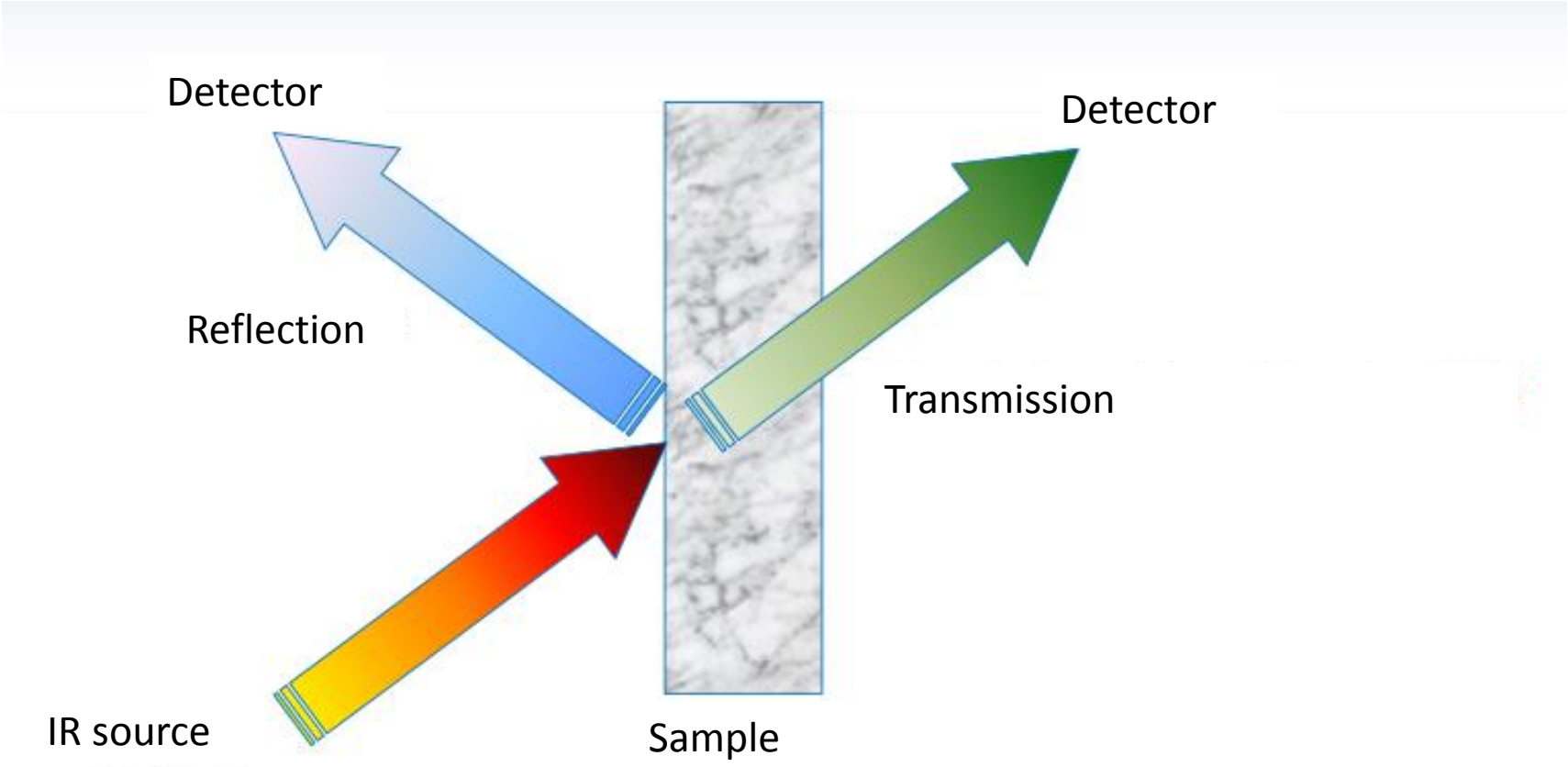
$$E = \left(n + \frac{1}{2}\right) h\nu$$

(quantized energy levels)

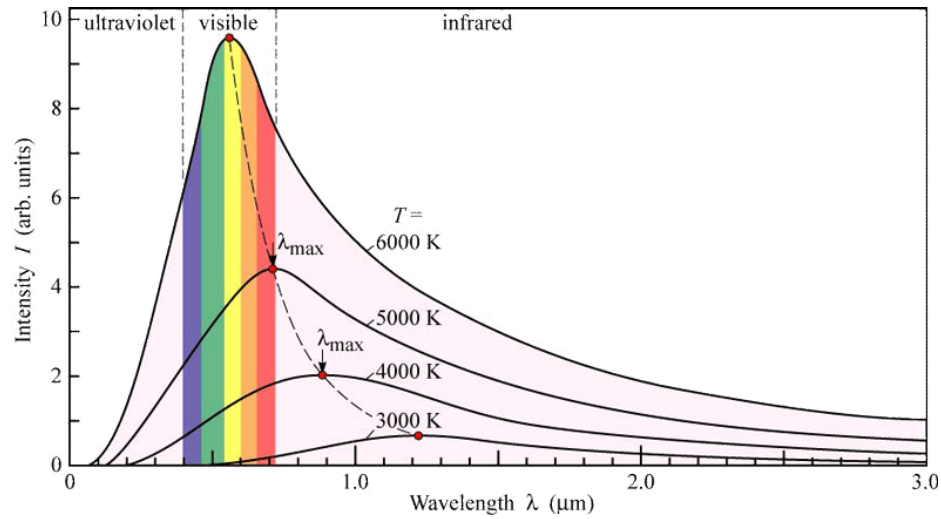
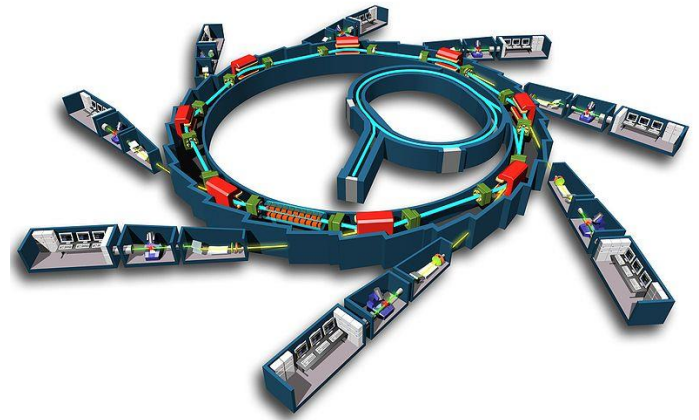
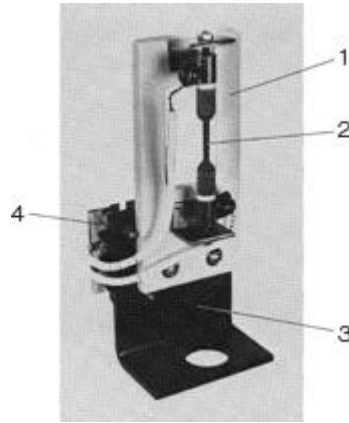
Figure 15.8 : Energy curve for an anharmonic oscillator (showing the vibrational levels for a vibrating bond).

- $3N-6$ (non linear molecule)
- $3N-5$ (linear molecule)

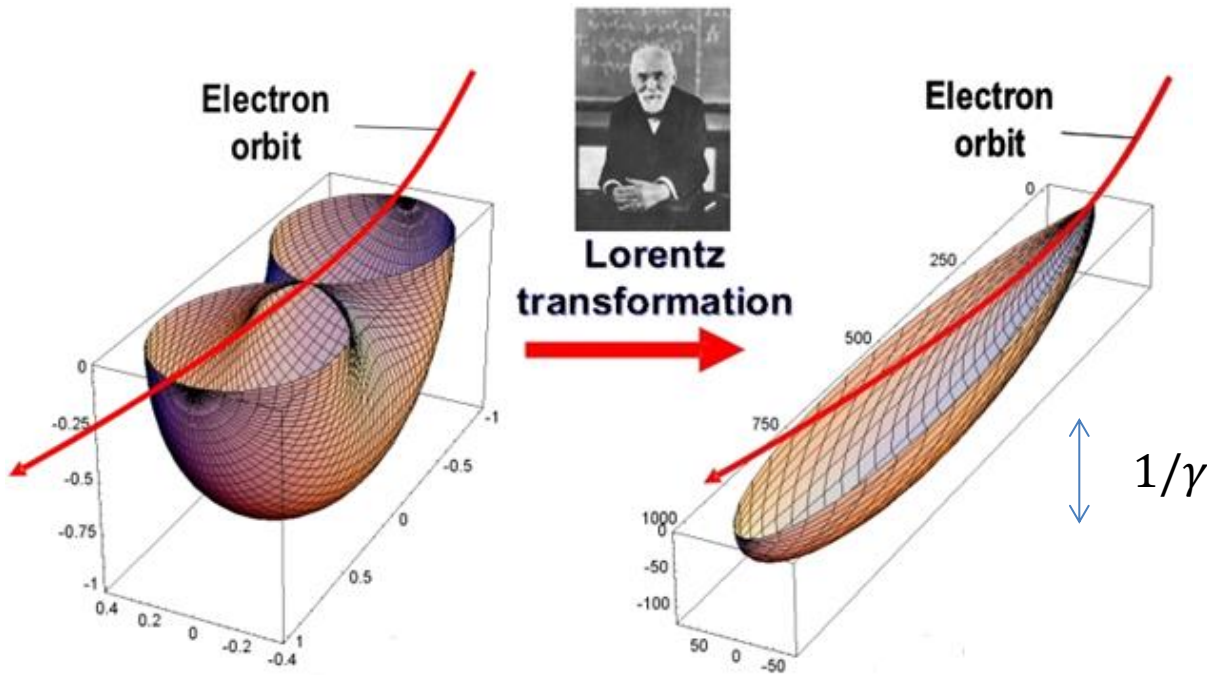
Fourier Transform Infrared Spectroscopy (FT-IR)



IR sources



Synchrotron radiation



Classic ($v \ll c$)

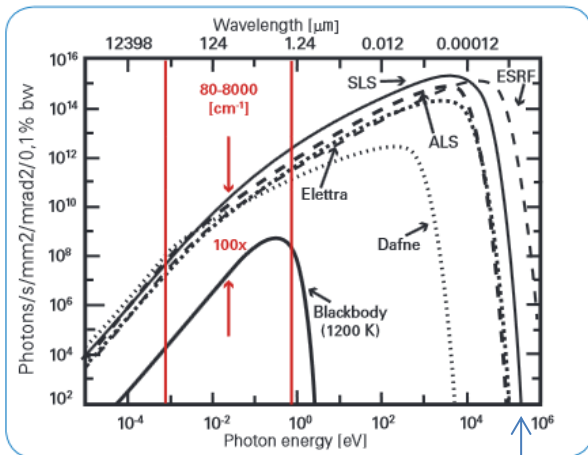
Relativistic ($v \approx c$)

Every moving electric charge emits EM radiation.

$$\beta = v/c$$

$$\gamma = \frac{1}{\sqrt{1 - \beta^2}}$$

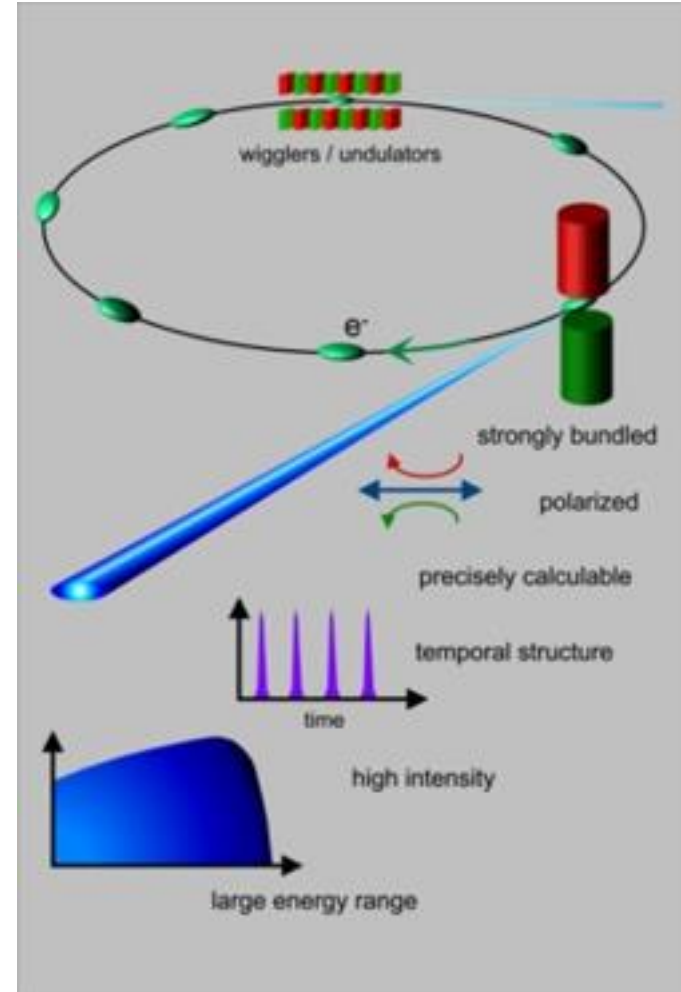
Per $\beta=0.99$ $1/\gamma = 10$ mrad



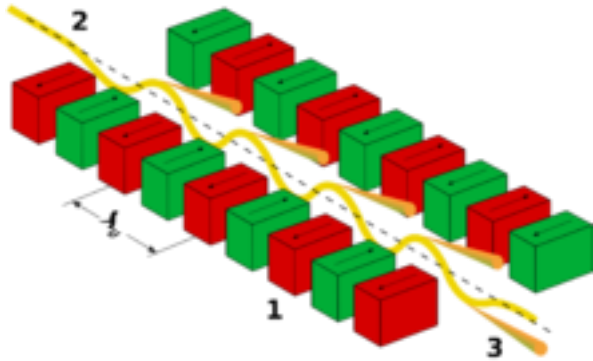
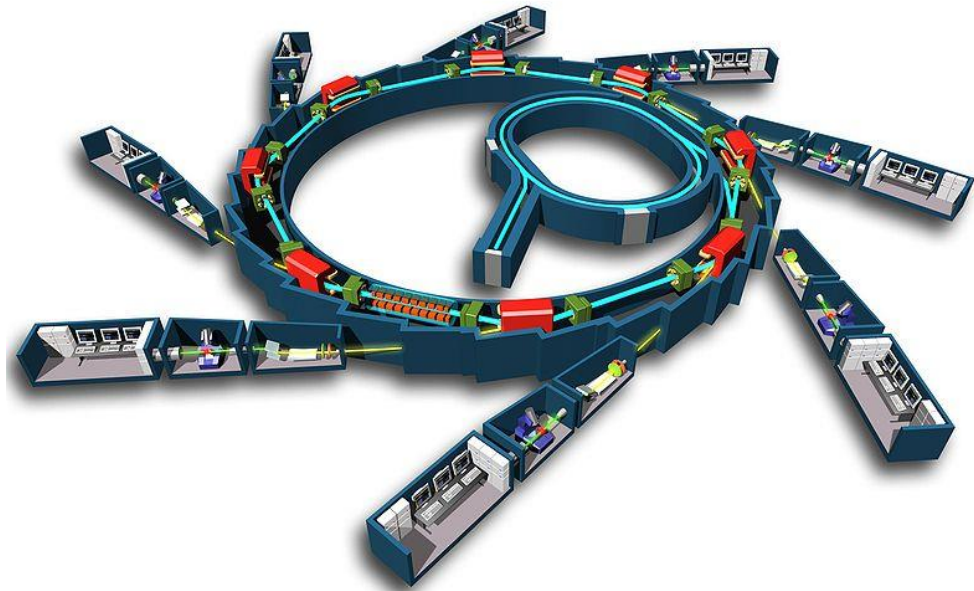
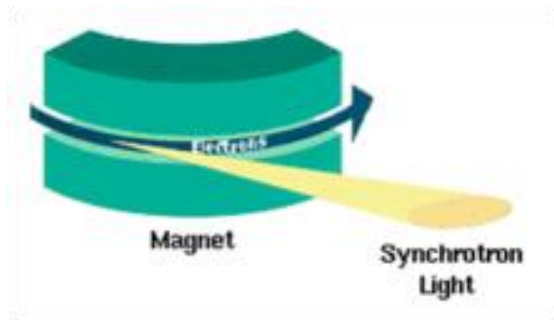
$$\text{brilliance} = \frac{\text{photons}}{\text{second} \cdot \text{mrad}^2 \cdot \text{mm}^2 \cdot 0.1\% \text{BW}}$$

Fig. 1: Advantages of the e-Synchrotron radiation source

Critical energy

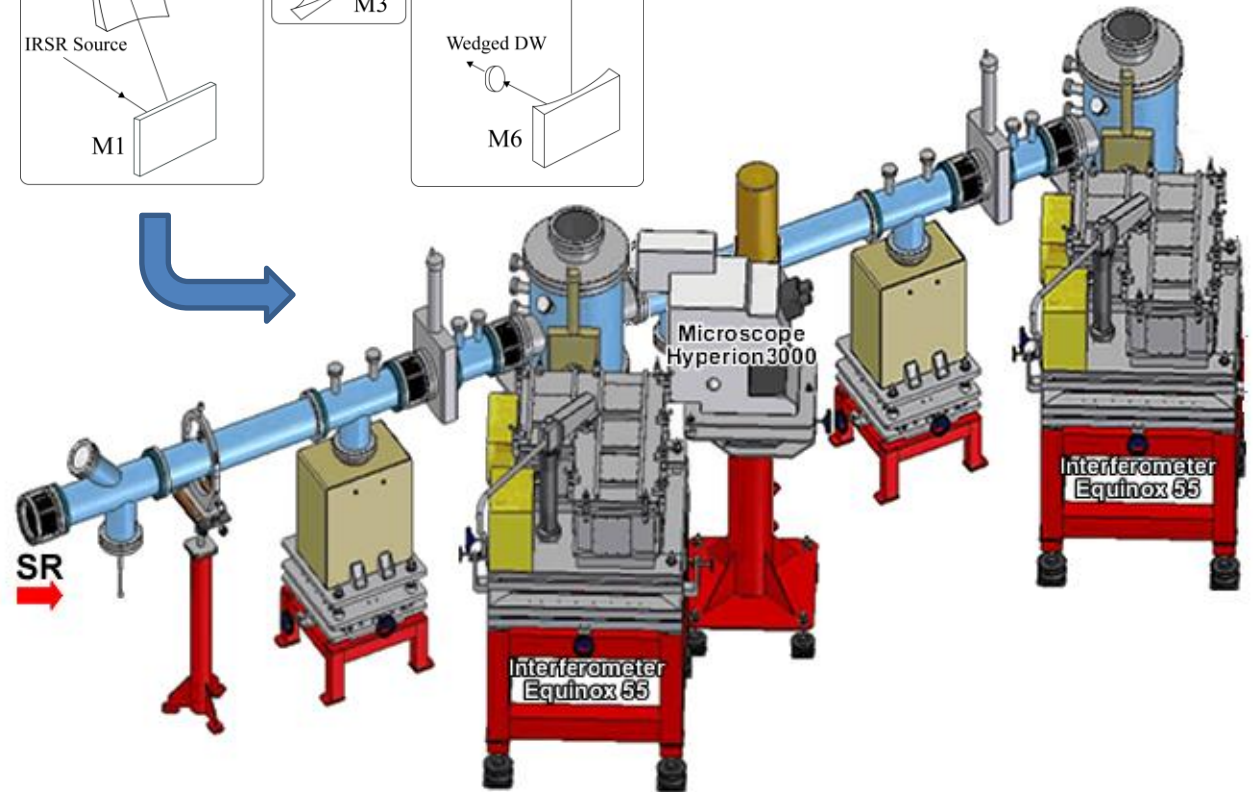
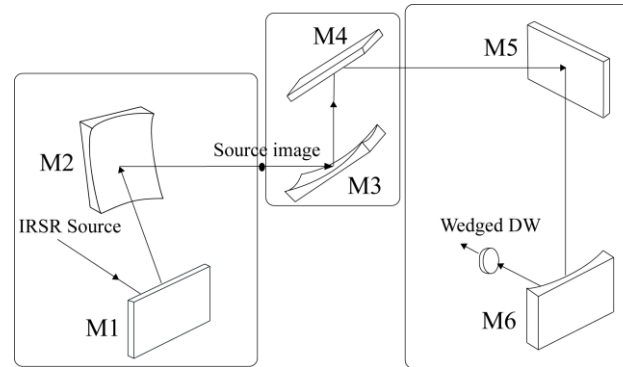
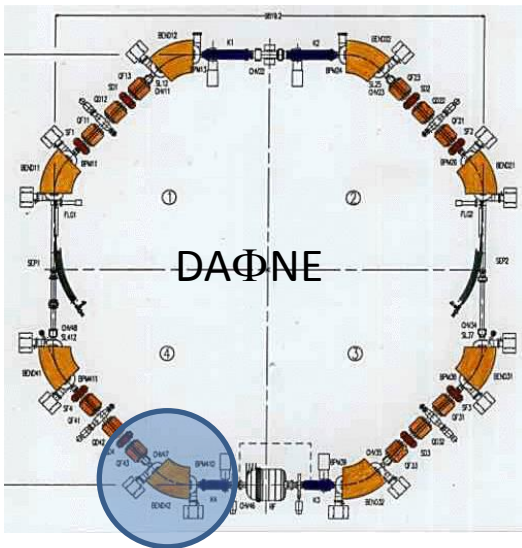


The beamlines

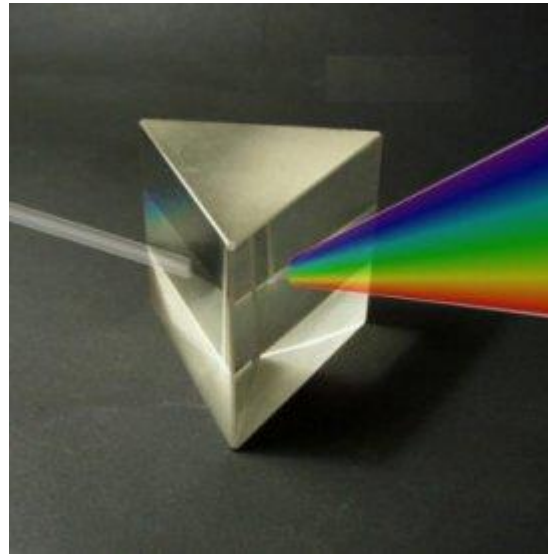


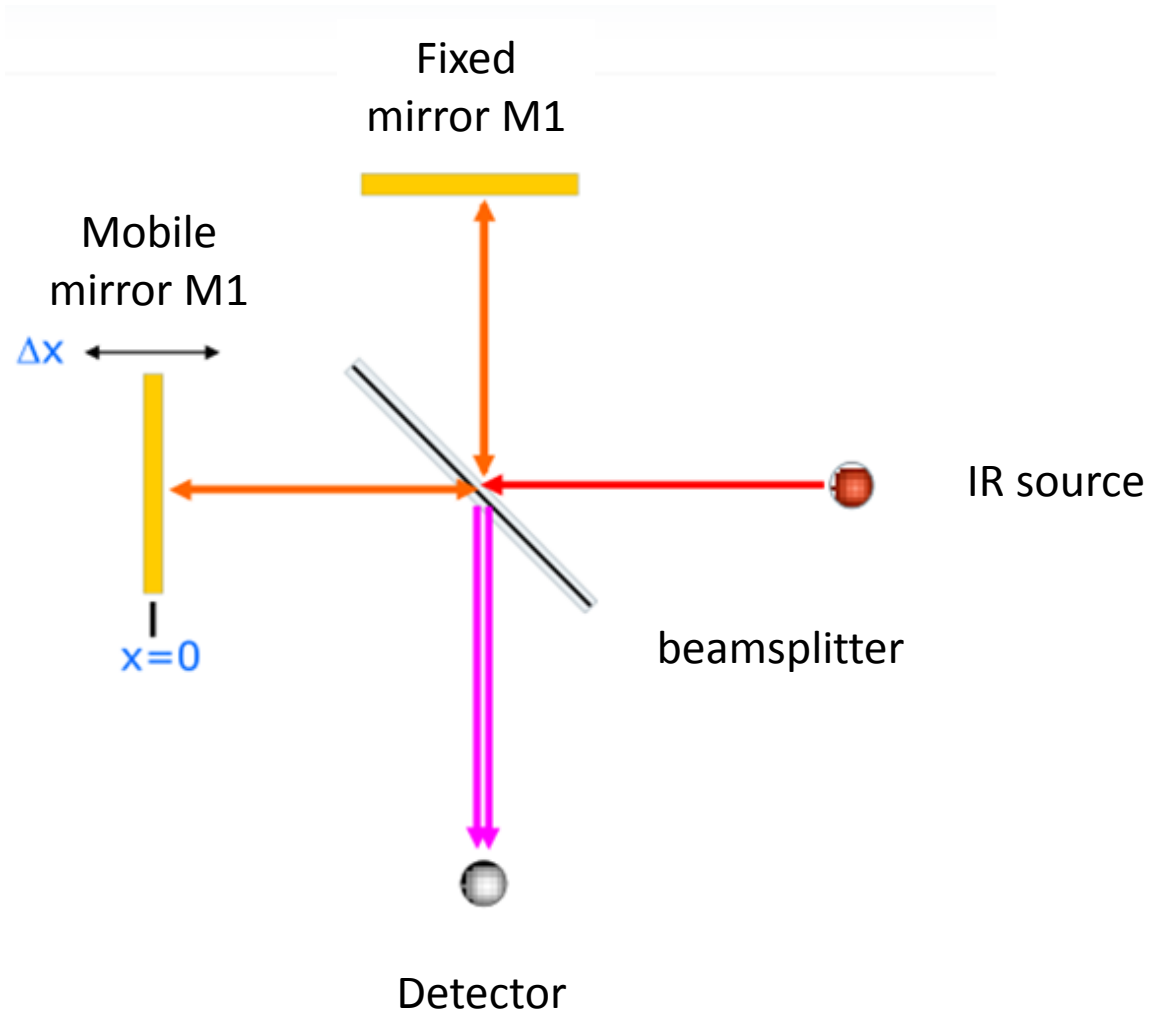
The IR SINBAD beamline

Infrared domain
from 10 to 10^3 cm^{-1}
 1.24meV to 1.24 eV

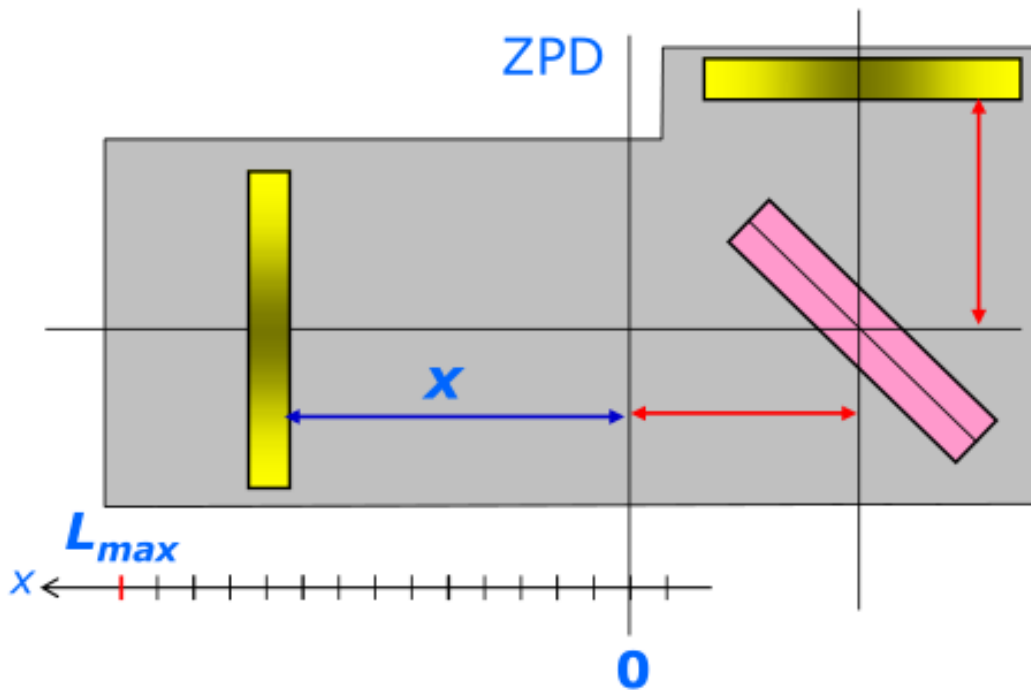


Michelson interferometer



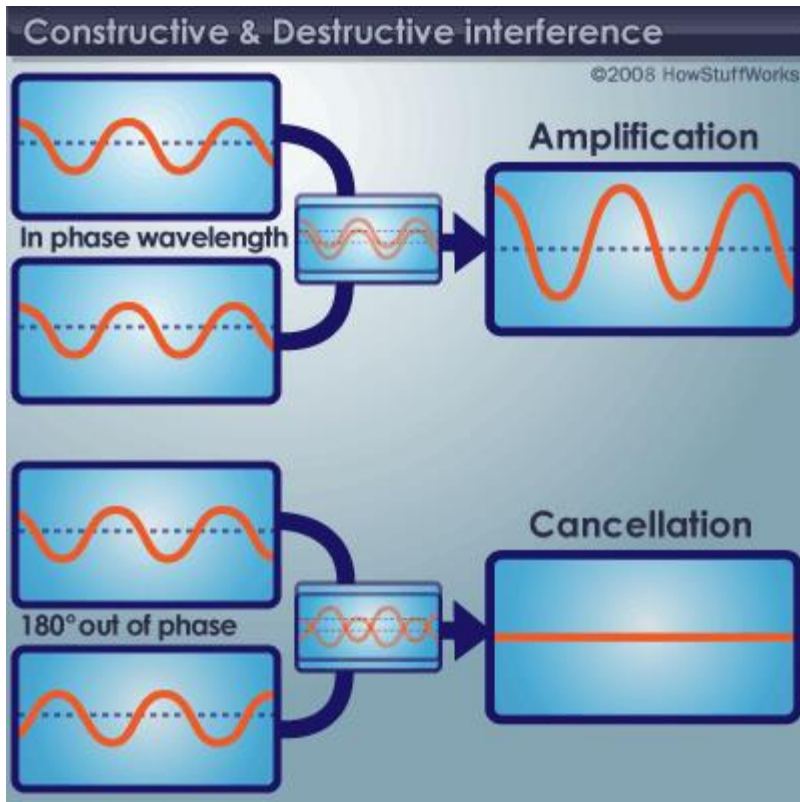


The interferogram depends on the optical path difference (OPD) between the two beams



The OPD is twice the mirror excursion x . Since the mirror speed v is constant:

$$2x = 2vt$$



$$\text{OPD} = 2n \frac{\lambda}{2} \quad (n = 0, \pm 1, \pm 2, \dots)$$

$$\text{OPD} = (2n+1) \frac{\lambda}{2} \quad (n = 0, \pm 1, \pm 2, \dots)$$



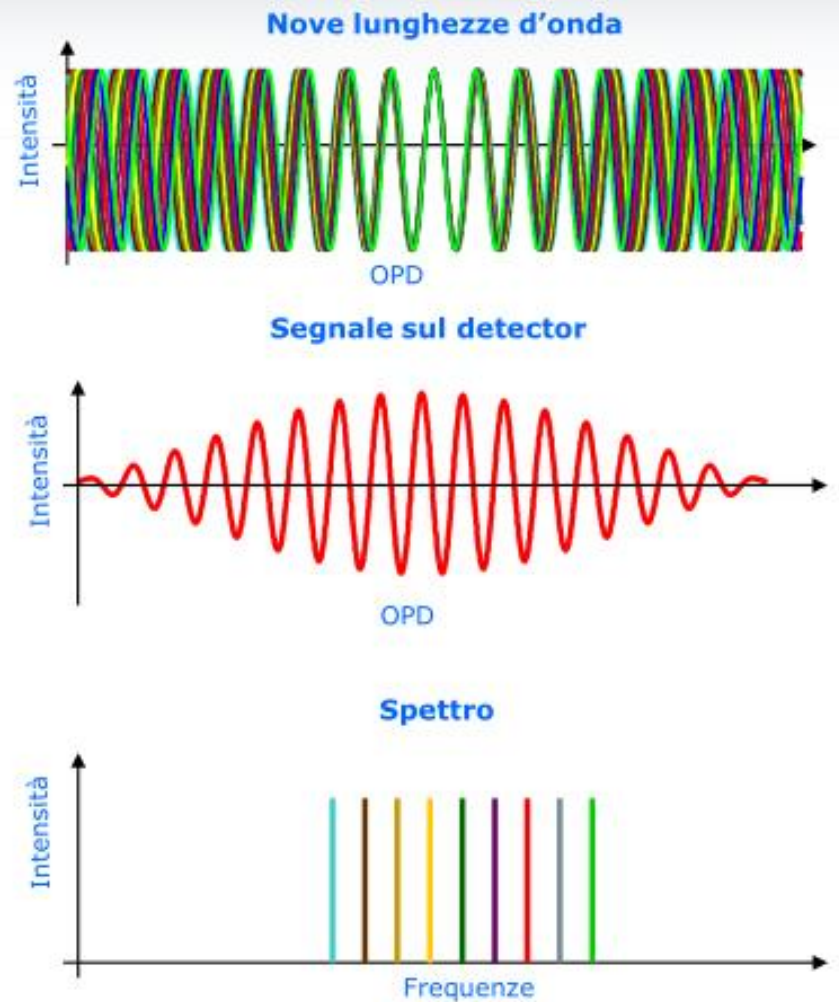
$$I(t) = S(\tilde{\nu}) \cdot \cos(\underbrace{2\pi 2\tilde{\nu} \nu t}_{\text{Modulation frequency}})$$

Modulation frequency

- Origine dell'interferogramma:
l'onda monocromatica

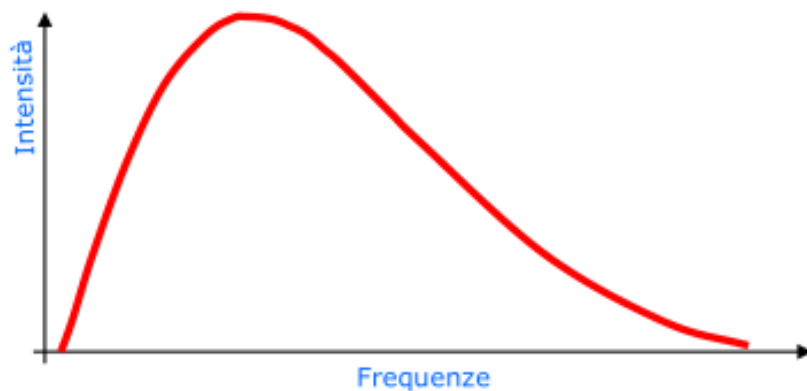


- Origine dell'interferogramma:
onda policromatica a componenti discrete



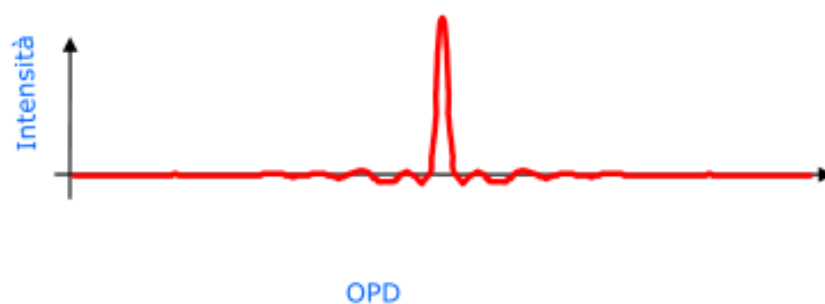
- Origine dell'interferogramma:
sorgenti a spettro esteso

IR-source



Distribuzione di frequenze di una sorgente di corpo nero

Segnale sul detector

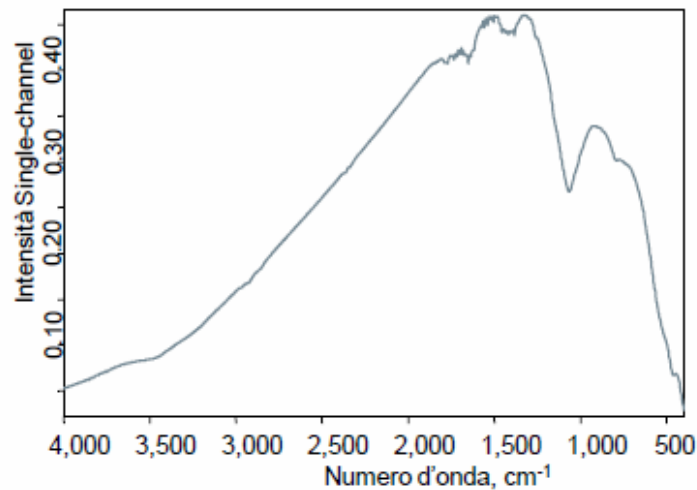
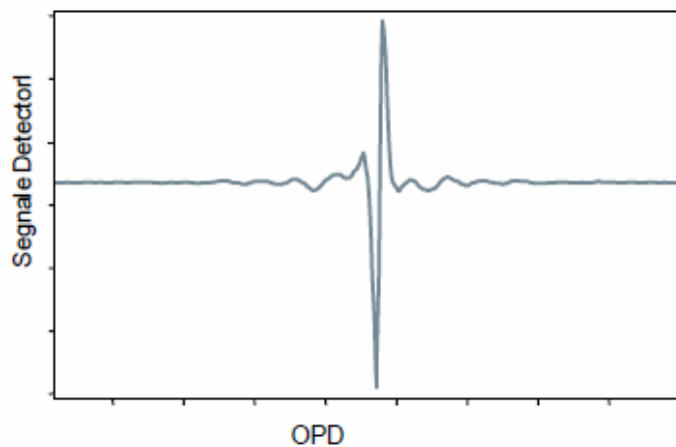


Interferogram

FT

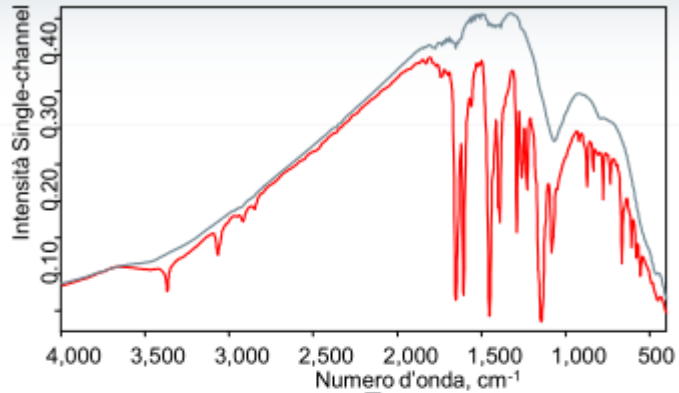
Spectrum

IFT

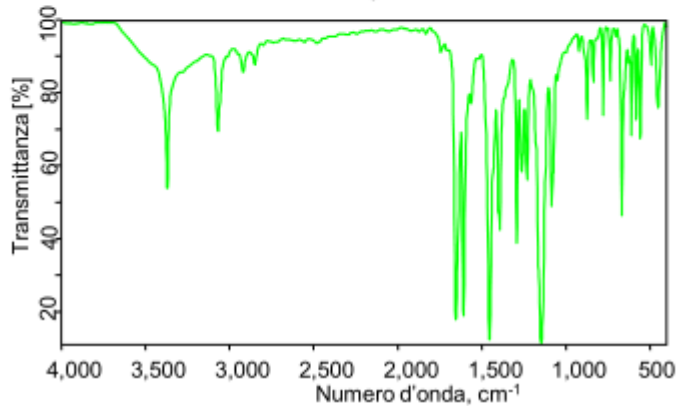


$$S(\nu) = \int_{-\infty}^{\infty} I(x) e^{i2\pi\nu x} dx$$

Measuring an IR spectrum

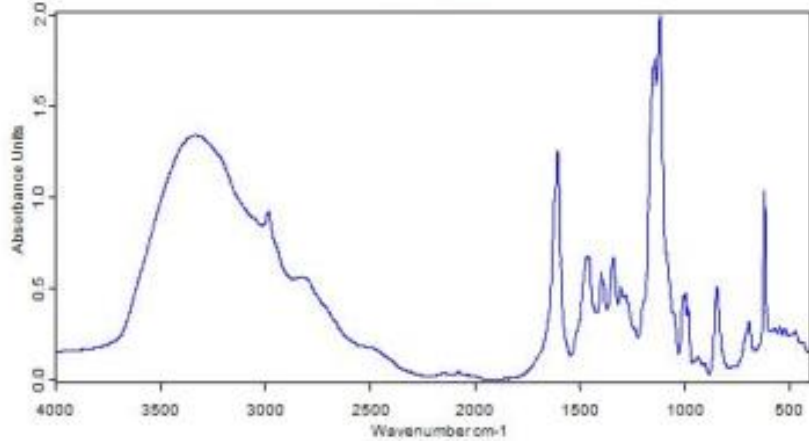
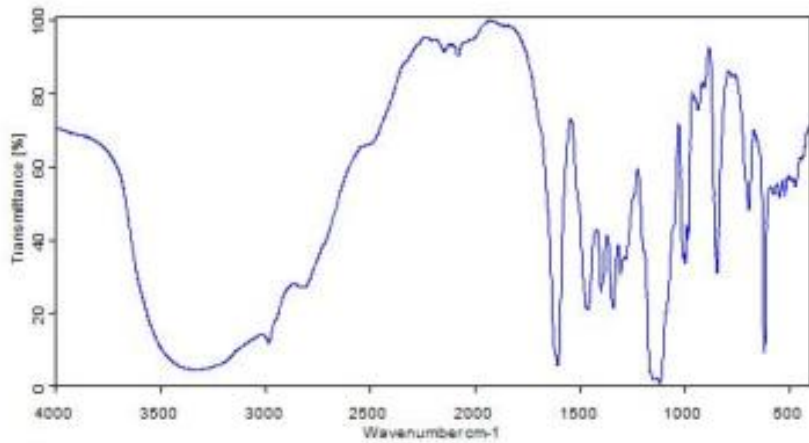


↓
Divisione



$$T(\nu) = \text{SSC}/\text{RSC}$$

TRANSMITTANCE



$$A = -\text{Log } T$$

ABSORBANCE

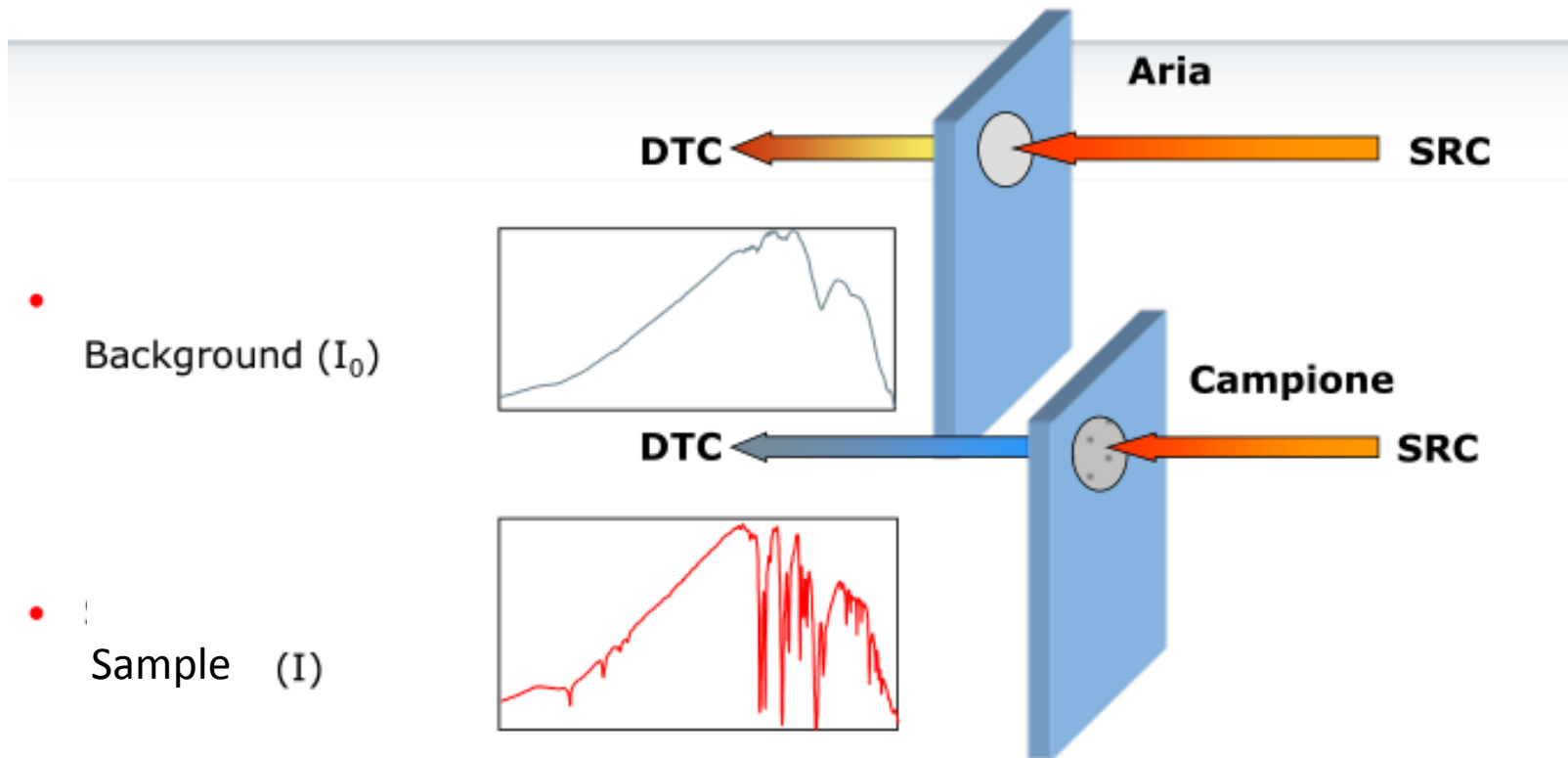
Sampling techniques

- Depending on the sample form (solid, liquid, powder, film) and which characteristics you want to maintain, it is possible to use different sampling techniques, **destructive** or **non destructive**:
- Transmission (liquids, powders, thin sections)
- Specular reflection (crystals, polished sections)
- Diffuse reflectance (powders)
- Attenuated Total Reflection (ATR) (thick samples, non reflecting surfaces)

Transmission KBr powder pellets



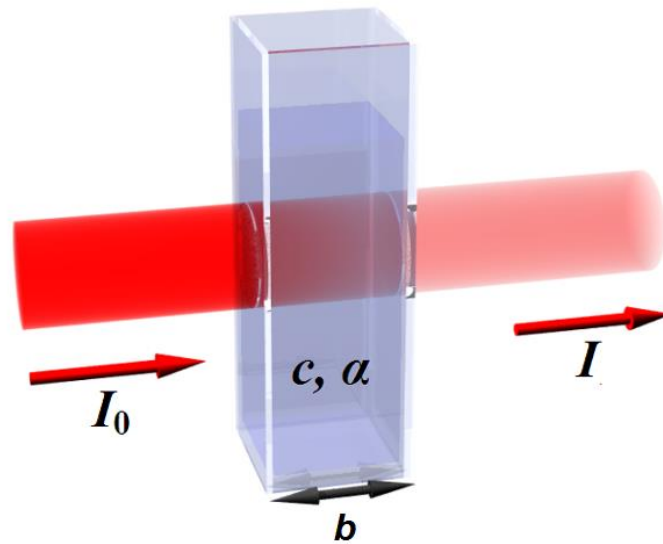
- Invasiva ☹️
- Distruttiva ☹️
- Laboriosa ☹️
- Molto precisa (misura assoluta) 😊
- Creazione di spettri di riferimento 😊



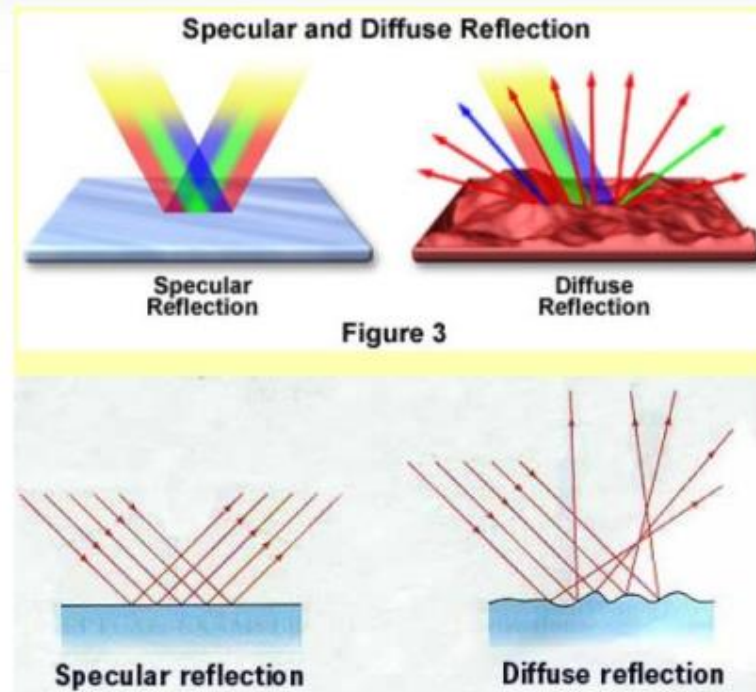
$$T = \frac{I}{I_0} \quad A = \log \frac{1}{T} = -\log T$$

Beer-Lambert law

$$A = \alpha b C$$



Reflection spectroscopy



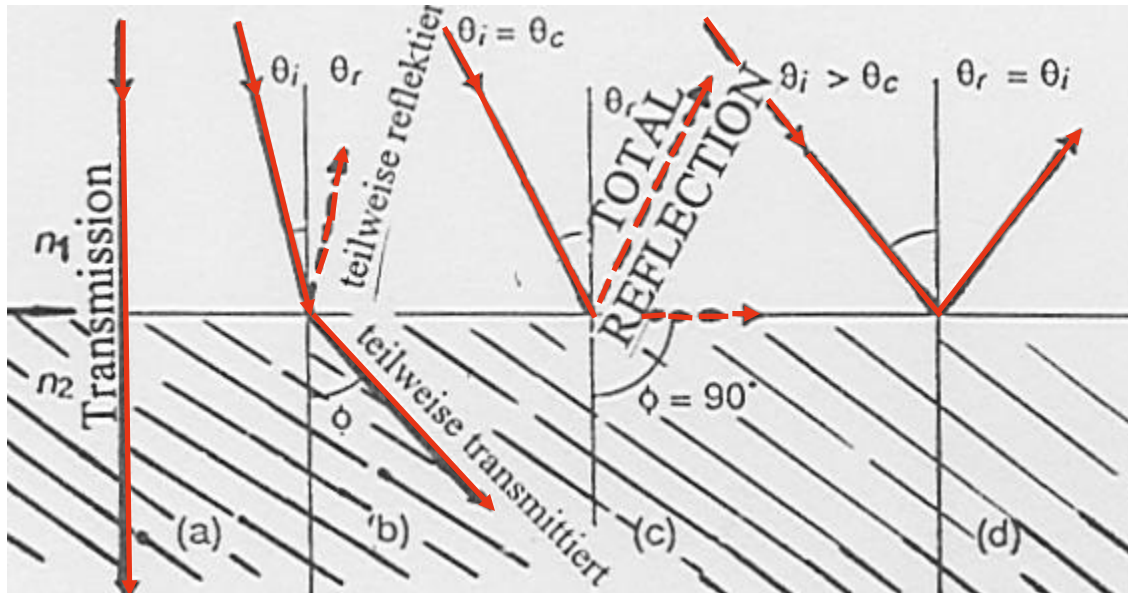
Preparation of the surface – polishing 😞

Thick samples 😊

Attenuated Total Reflection (ATR)



Principles of Attenuated Total Reflection spectroscopy (ATR)



Crystal n_1

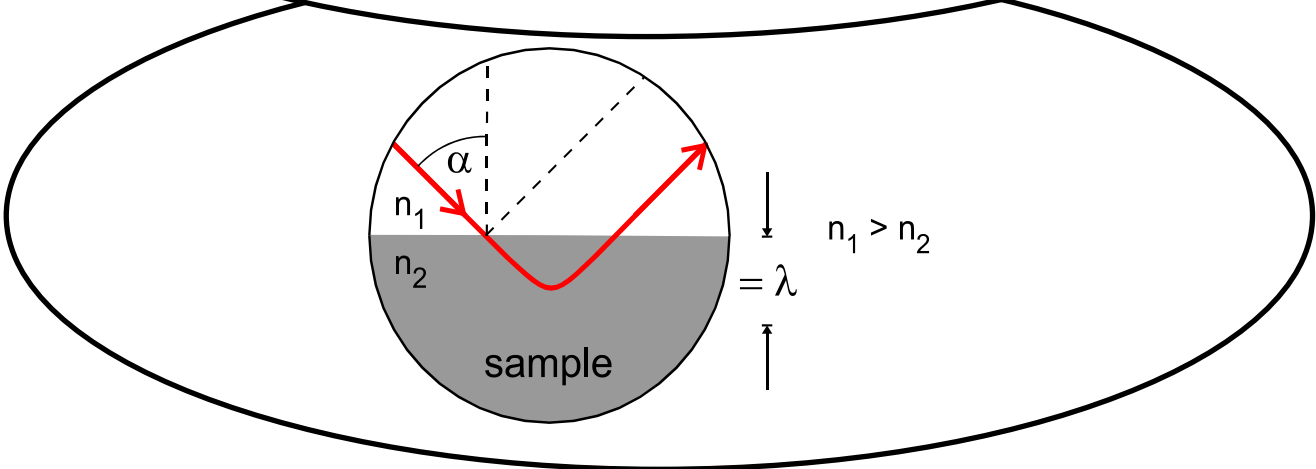
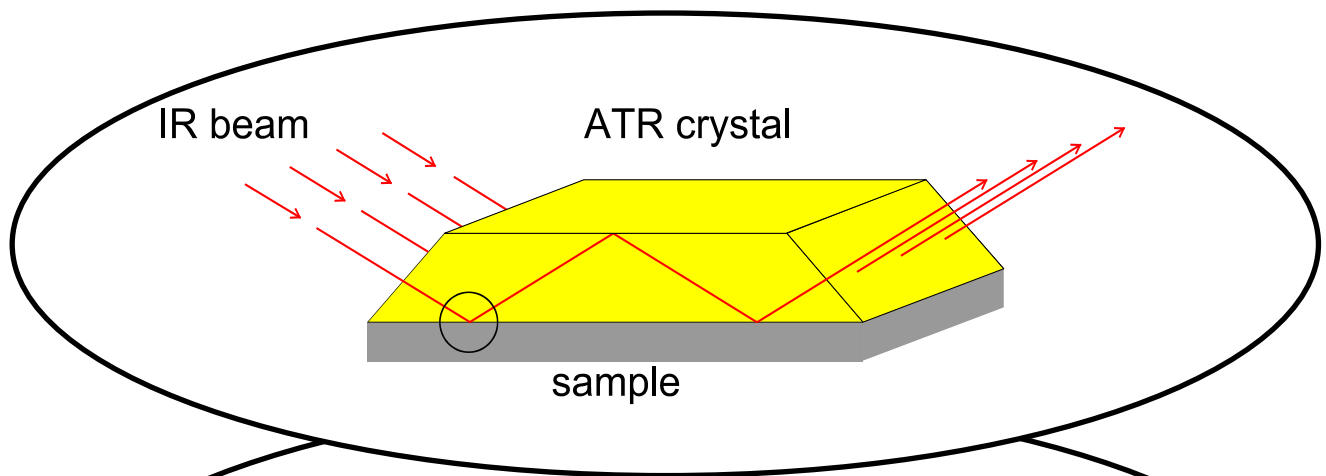
Sample n_2

Snell's law: $n_1 \times \sin\Theta_i = n_2 \times \sin\Theta_r$

Critical angle: $\Theta_r = 90^\circ$

$$\sin\Theta_c = n_2 / n_1$$

(es. 38° for ZnSe for a sample with $n=1.5$)

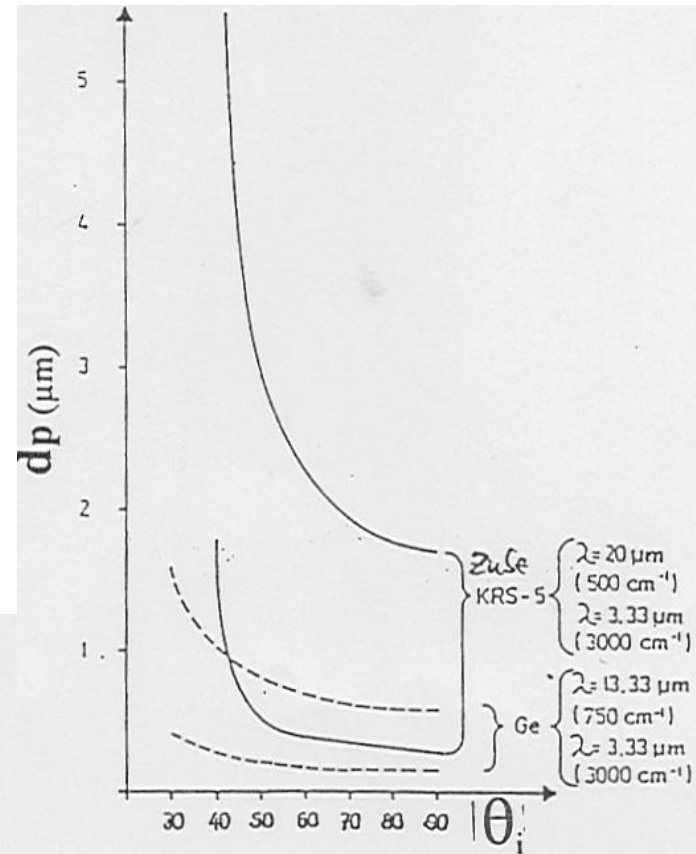


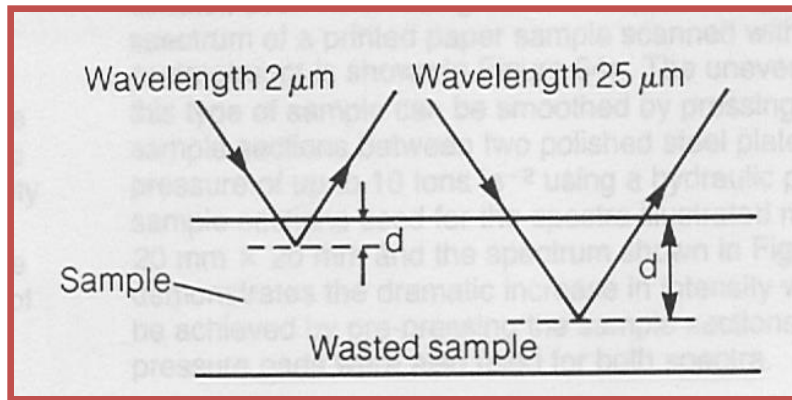
Penetration depth

$$d_p = \frac{\lambda}{2 \pi n_1 (\sin^2 \theta_i - n_{21}^2)^{1/2}}$$

θ_i	30°	45°	60°
KRS-5	$i\lambda$	0.290λ	0.113λ
Ge	0.091λ	0.041λ	0.002λ

(i = total transmission, sample index = 1.5)





$d_p \text{ prop } \lambda$

$$\text{ATR} = \text{AB} * \nu [\text{cm}^{-1}] / 1000 [\text{cm}^{-1}]$$

- Quick 😊
- Non invasive 😊
- (semi)destructive 😞

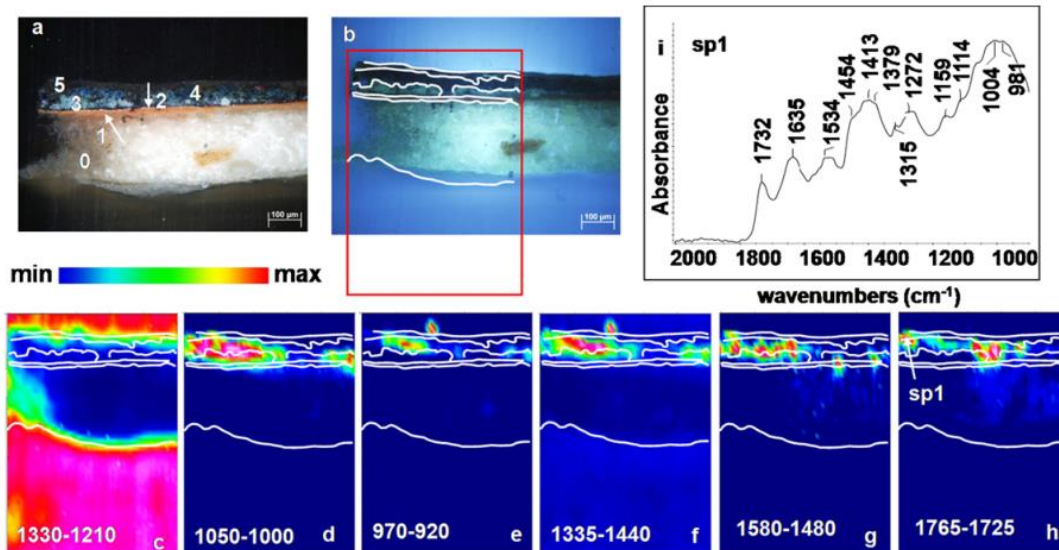
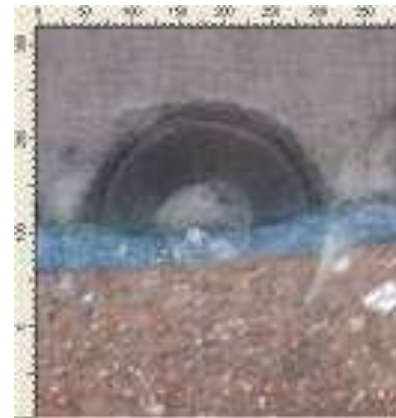
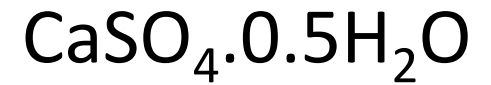
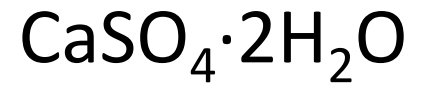
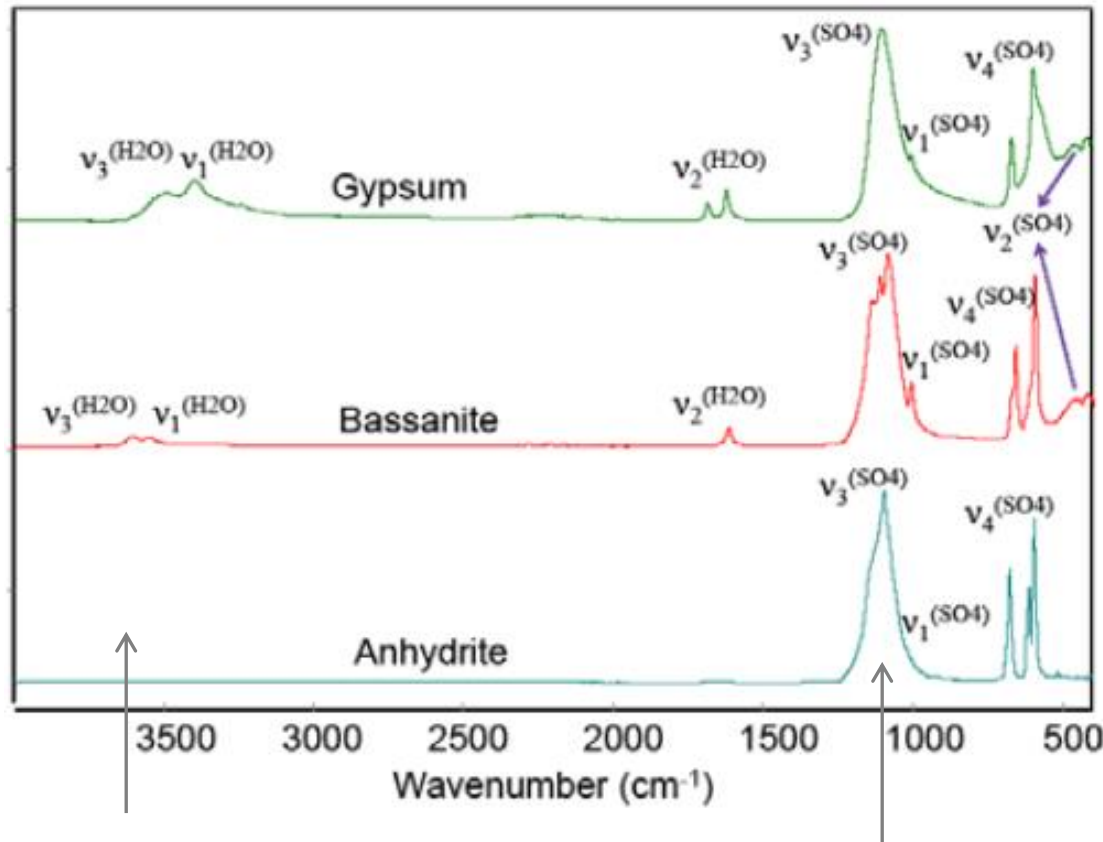


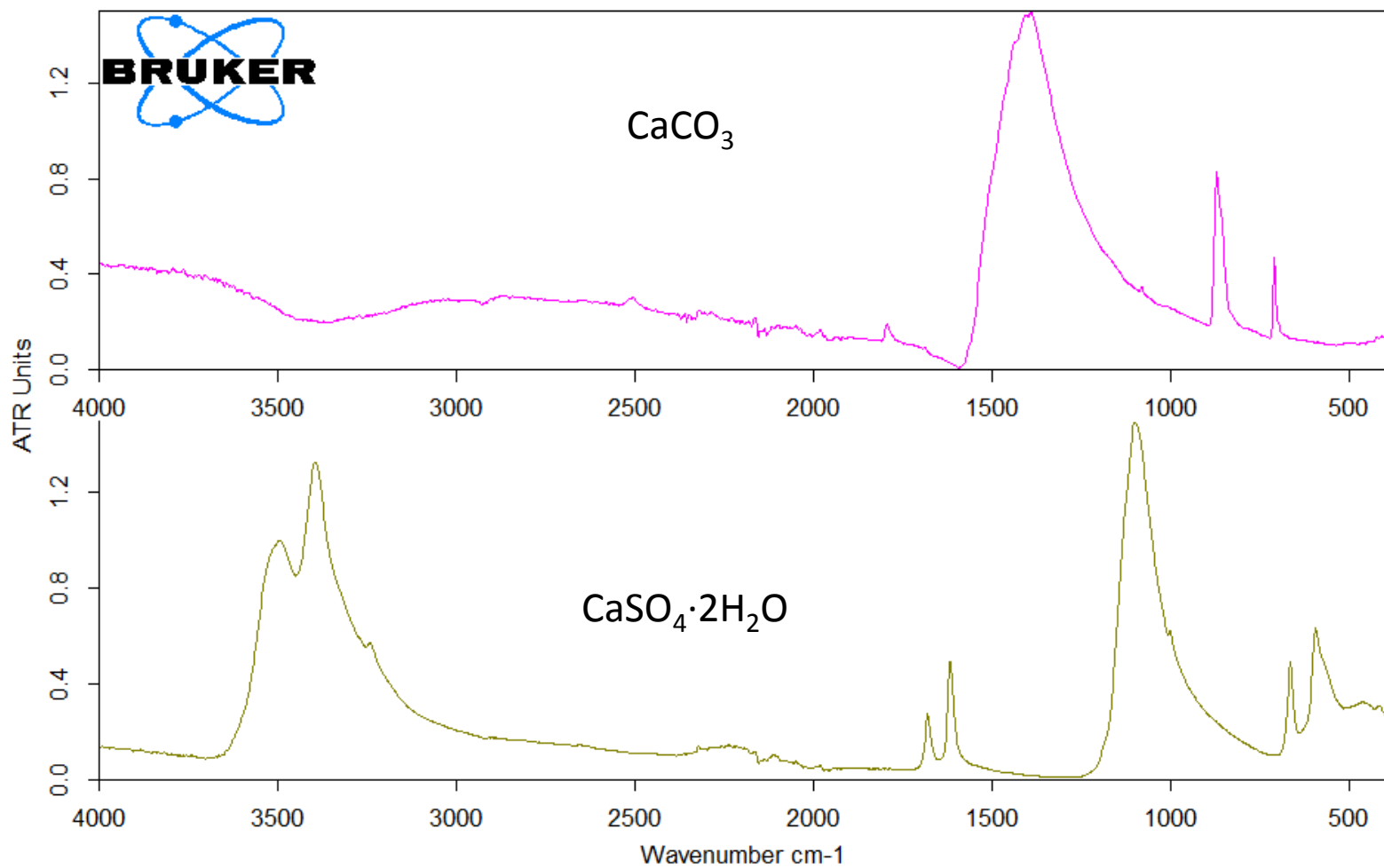
Fig. 2. Detail of a cross-section from the polychrome sculpture (Fe2): (a) visible microscopic image; (b) image of sample under ultraviolet light; (c) FT-IR image created by plotting the integrated absorbance of the embedding resin band between 1330 and 1200 cm^{-1} ; (d) FT-IR image showing the distribution of the silicate integrated absorbance between 1050 and 1000 cm^{-1} ; (e) FT-IR image showing the distribution of the azurite integrated absorbance between 970 and 920 cm^{-1} ; (f) FT-IR image showing the distribution of the carbonate integrated absorbance between 1335 and 1440 cm^{-1} ; (g) FT-IR image showing the distribution of the amide II integrated absorbance between 1580 and 1480 cm^{-1} ; (h) FT-IR image showing the distribution of the triglycerides integrated absorbance between 1765 and 1725 cm^{-1} ; (i) FT-IR spectrum extracted from the right area of h, marked sp1. The size of the FT-IR images is 700 $\mu\text{m} \times 500 \mu\text{m}$. The figure is available in colour in the online version via Science Direct.

ATR spectrum of gypsum



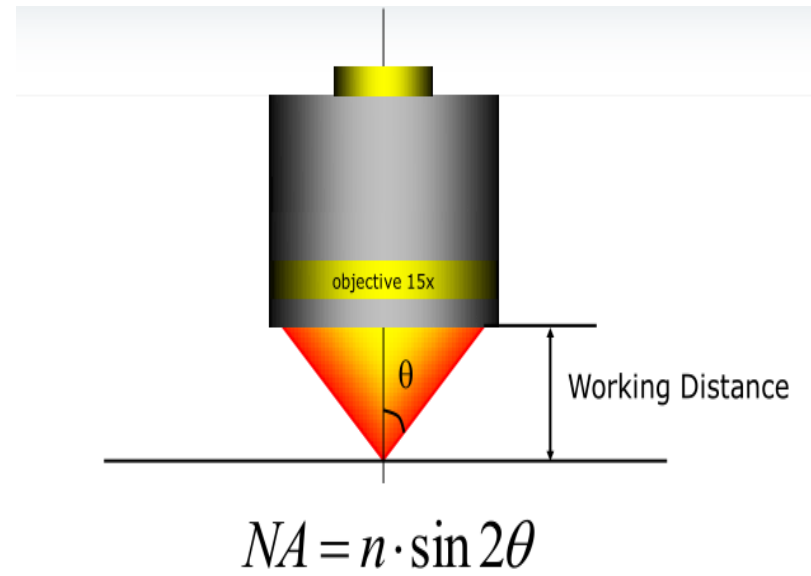
Water molecule:
Stretching symmetric
and antisymmetric of H₂O

v₃ Stretching antisymmetric of SO₄ tetrahedra
v₁ Stretching symmetric of SO₄ tetrahedra



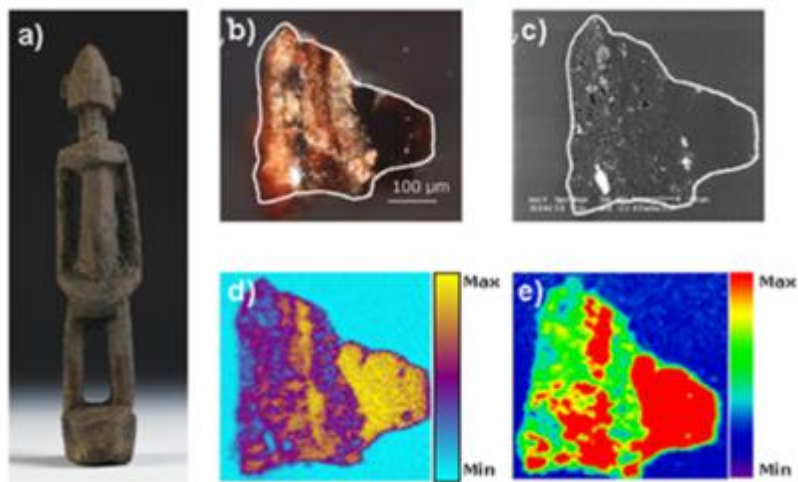
C:\Users\Mariangela\Documents\AAA-Misure, Analisi dati\mb	\Libreria BOPT Beni Culturali\Calcium Carbonate CaCO3 P-ATR.0	28/04/2010
C:\Users\Mariangela\Documents\AAA-Misure, Analisi dati\mb	\Libreria BOPT Beni Culturali\Calcium Sulfate CaSO4 P-ATR.0	28/04/2010

Microscopy and Imaging



The IR microscope is essentially a beam condenser

FTIR imaging



Study of the patina sample from a Dogon statuette:

- a) Photograph of the object, Quai Branly Museum, inventory no 71.1935.105.169, (copyright C2RMF, D. Vigears);
- b) Dark field microscopic view of the cross-section of the sample;
- c) Backscattered electron micrograph;
- d) ToF-SIMS image of protein fragment ions;
- e) SR-µFTIR image of proteins.

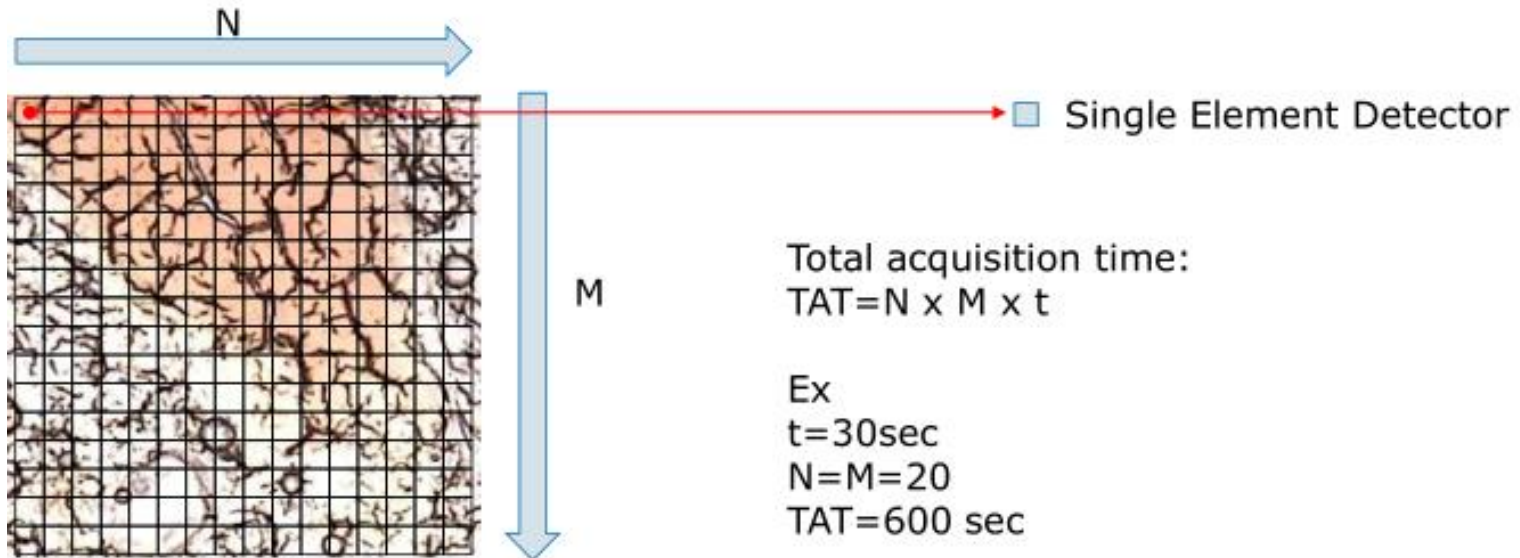
Vincent Mazel et al, (2007).

Analytical Chemistry. DOI : 10.1021/ac070993k

Mapping vs imaging

Mapping:

- Campione
- Stage portacampioni automatico gestito da PC
- Rivelatore a singolo elemento (MCT, $250\mu\text{m}$)



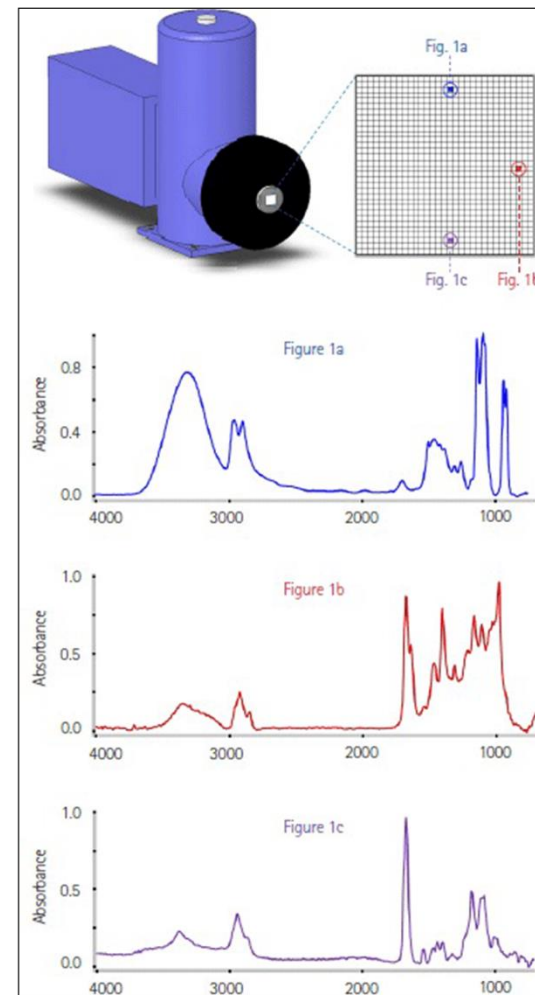
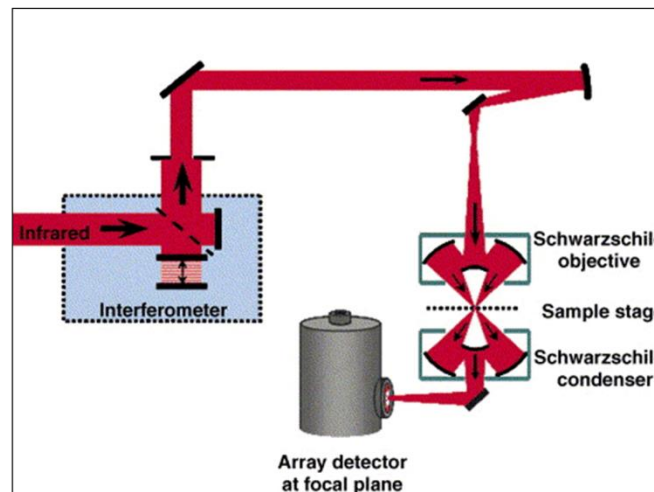
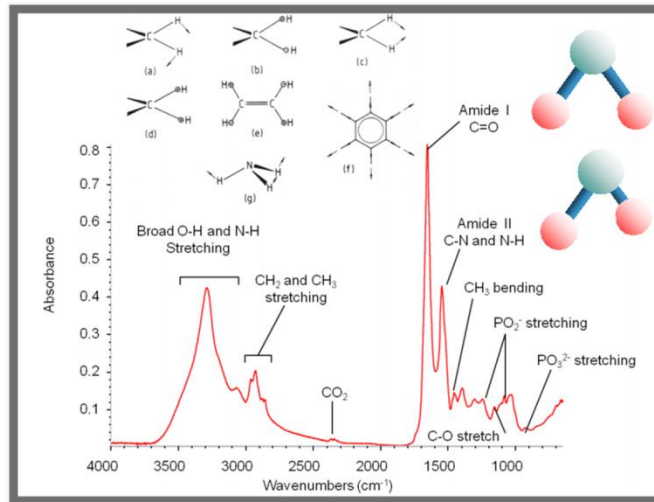
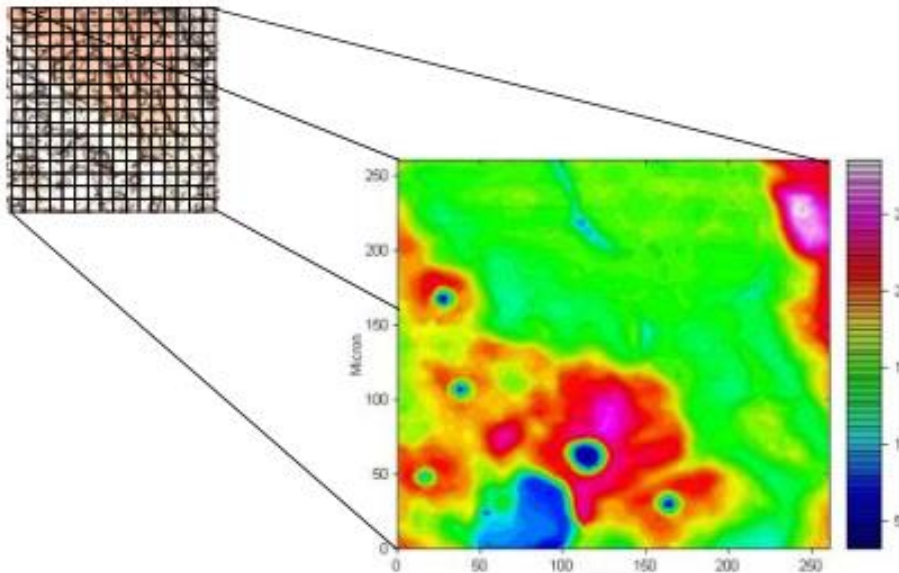


Figura 2: (a) Lo spettro IR di un composto organico mostra gli assorbimenti dovuti alle vibrazioni molecolari. (b) Schema ottico del microscopio IR accoppiato allo spettrometro ed al detector FPA. (c) Schema di funzionamento di un detector FPA.

Imaging:

- Campione
- Stage portacampioni non necessariamente automatico
- Focal Plane Array Detector (64x64, 128x128, 256x256 – pixel da 40 μ m)



Total acquisition time:
 $TAT=t$

In t we are acquiring a
 $N \times N$ matrix of spectra

APPLICATION TO THE STUDY OF PAINTING CROSS SECTIONS

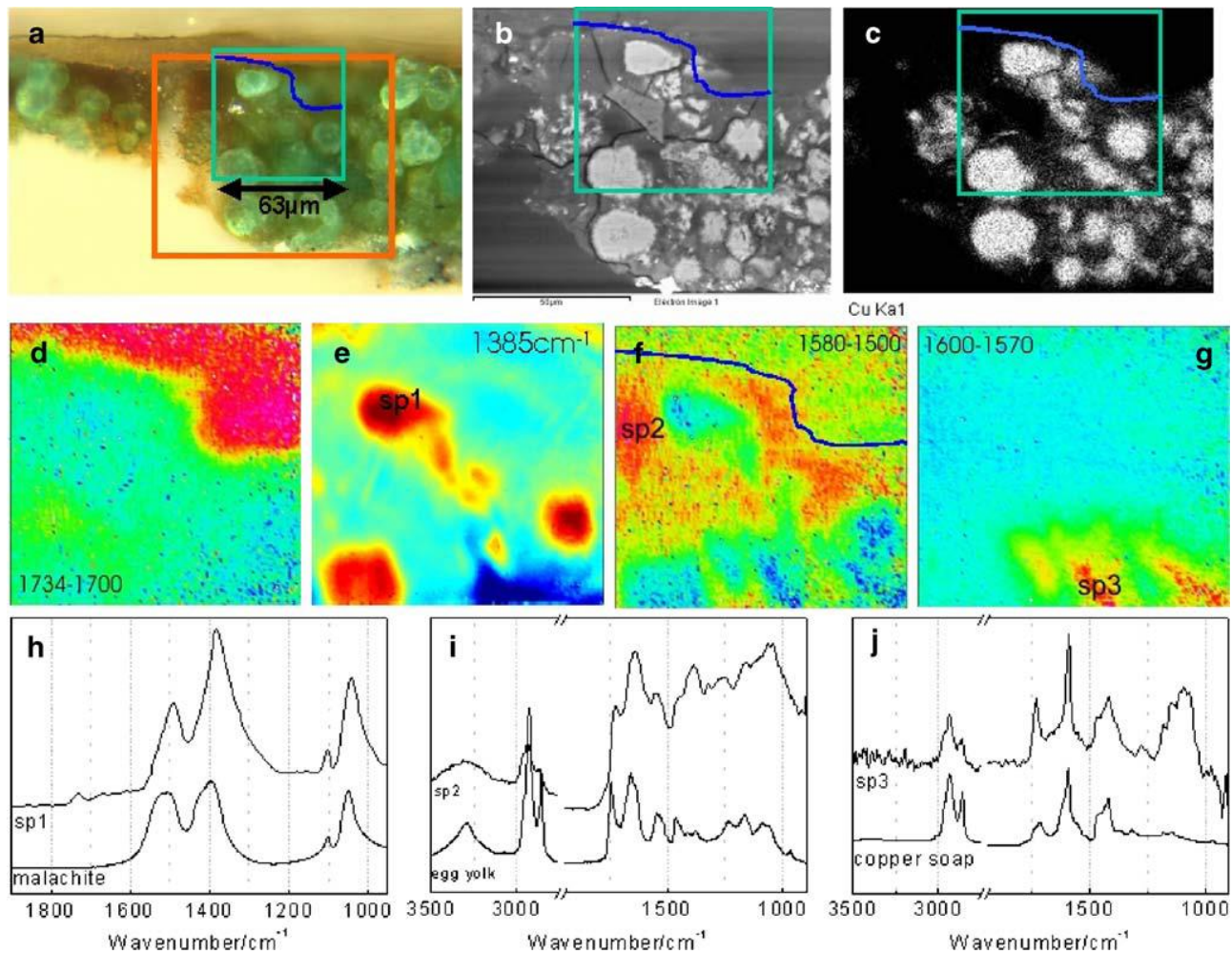


Figura 1. Sezione stratigrafica di un frammento prelevato dalla veste verde di un dipinto raffigurante la Madonna col Bambino: a) sezione stratigrafica al microscopio ottico in luce visibile; b) immagine ottenuta al microscopio elettronico (SEM); c) mappatura dell'elemento rame (Cu) eseguita mediante spettrometro a raggi X al microscopio elettronico (SEM-EDS); d) distribuzione della resina poliesteri ottenuta mediante FTIR FPA-imaging; e) distribuzione del pigmento verde malachite, ottenuta mediante FTIR FPA-imaging; f) distribuzione di legante proteico, ottenuta mediante FTIR FPA-imaging; g) distribuzione di olio siccativo ottenuta mediante FTIR FPA-imaging; h) spettro di assorbimento della particella verde e del riferimento della malachite; i) spettro della componente proteica e del riferimento del rosso d'uovo; j) spettro ottenuto da una zona contenente olio siccativo e lo spettro di riferimento di una "sapone" formatosi per reazione tra rame e olio siccativo – immagine tratta dal testo citato – nota 3



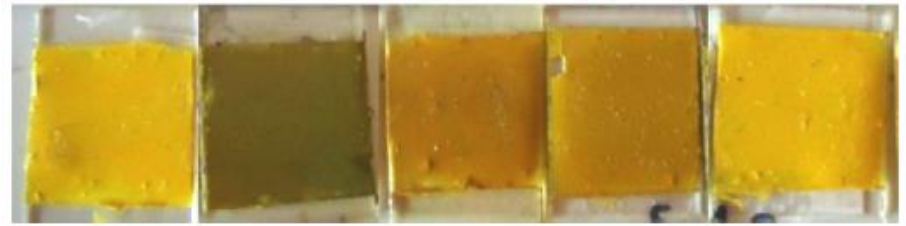
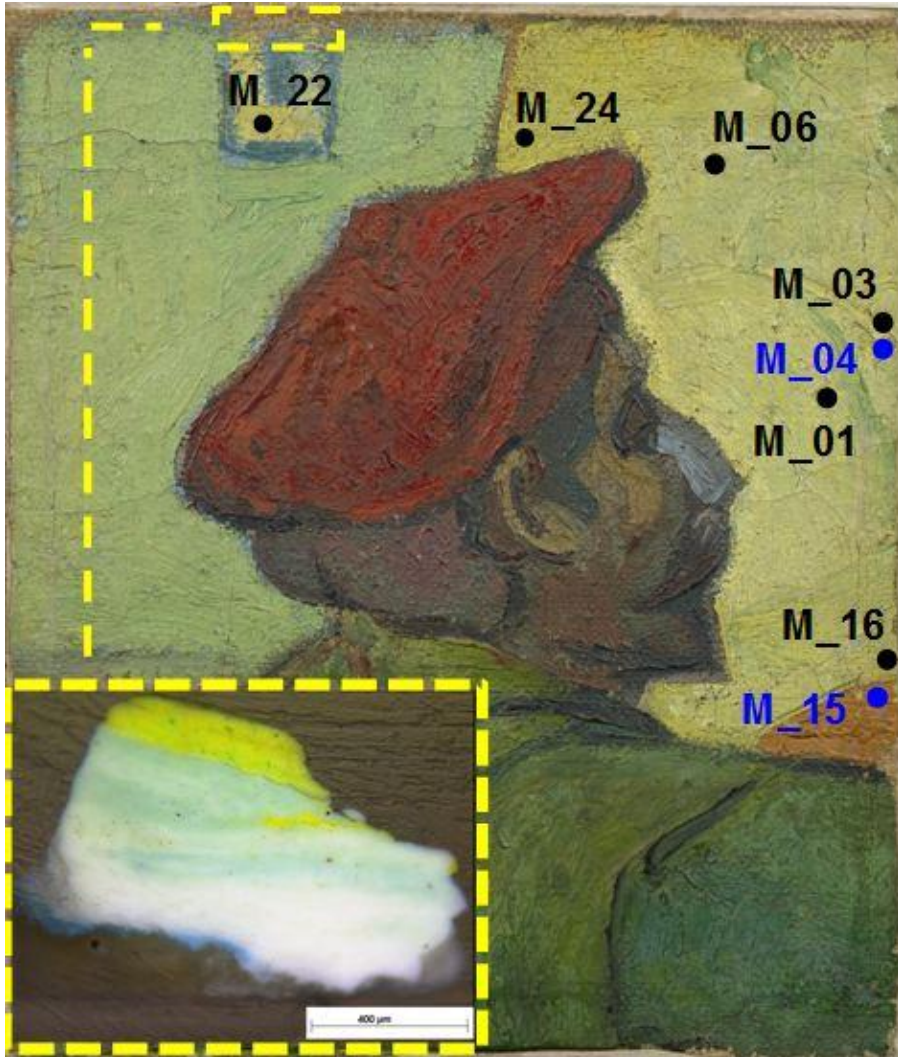
Studio dei processi di degradazione dei pigmenti gialli di Van Gogh



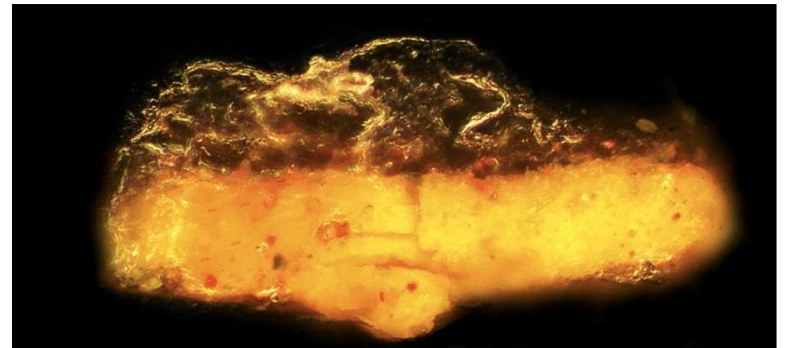
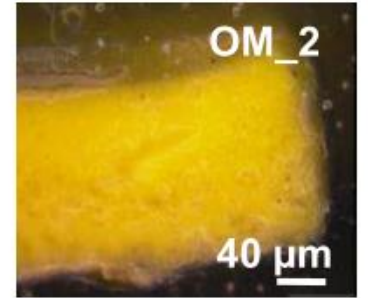
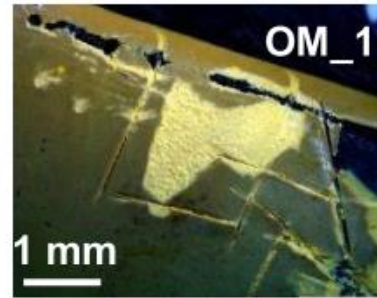
VAN GOGH
MUSEUM
AMSTERDAM



<http://www.vangogh.ua.ac.be/>



unaged "UVA-Vis" "UV" "blue" "red"



Alcuni spettri di riferimento

Courtesy of Centro Conservazione e Restauro
La Venaria Reale



Il carbonile

C-H	2960-2850	stretch
	1470-1350	scissoring and bending
	1380	- Doublet - isopropyl, <i>t</i> -butyl
C-H	3080-3020	stretch
	1000-675	bend
C-H	3100-3000	stretch
	870-675	bend
	2000-1600	fingerprint region
C-H	3333-3267	stretch
	700-610	bend
C=C	1680-1640	stretch
C≡C	2260-2100	stretch
C=C	1600, 1500	stretch
C-O	1260-1000	stretch
C=O	1760-1670	stretch
O-H	3640-3160	stretch
	3600-3200	stretch
	3000-2500	stretch
N-H	3500-3300	stretch
	1650-1580	bend
C-N	1340-1020	stretch
C≡N	2260-2220	stretch

Solventi
Leganti
Vernici
Fibre

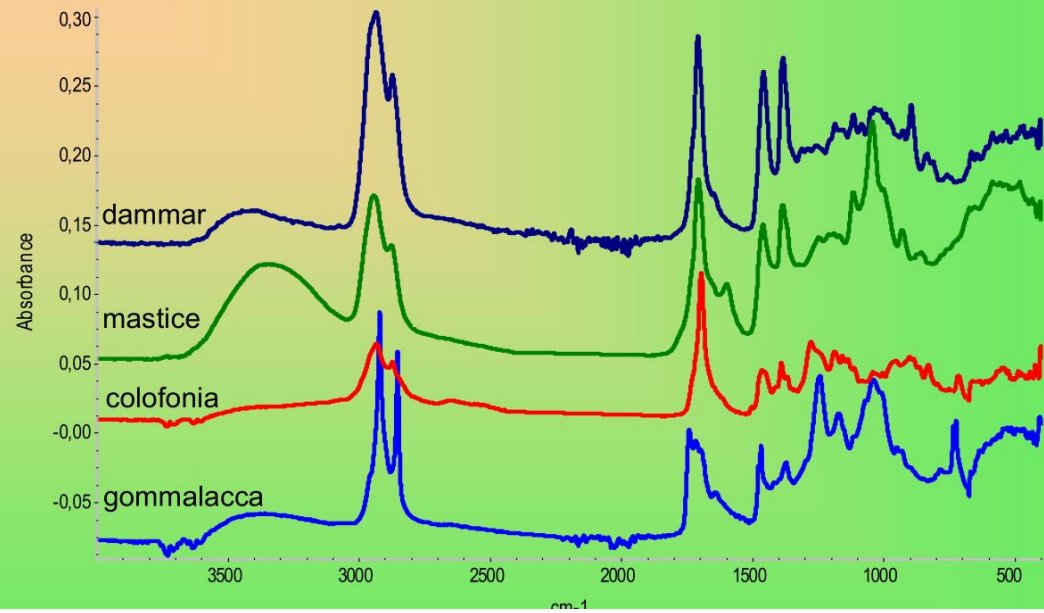
Ma anche in alcuni pigmenti inorganici

Gli esteri

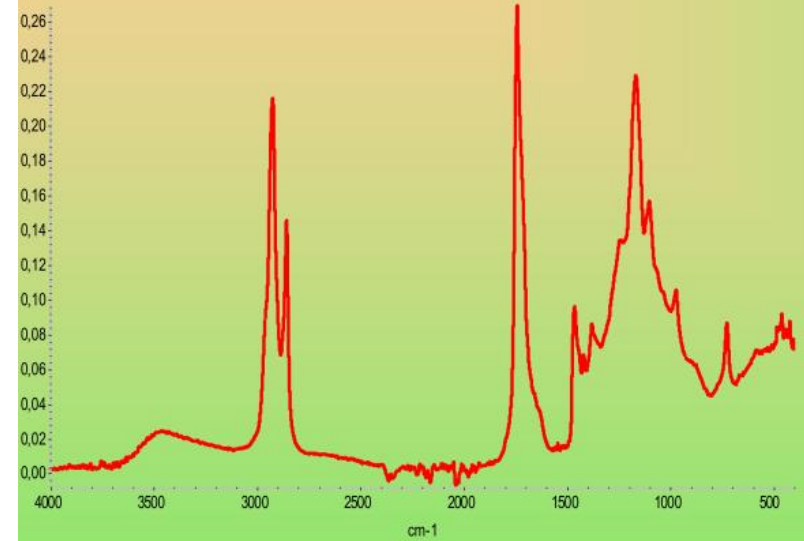


Oli siccativi
Resine naturali
Cere
Resine sintetiche
Additivi
Plastiche

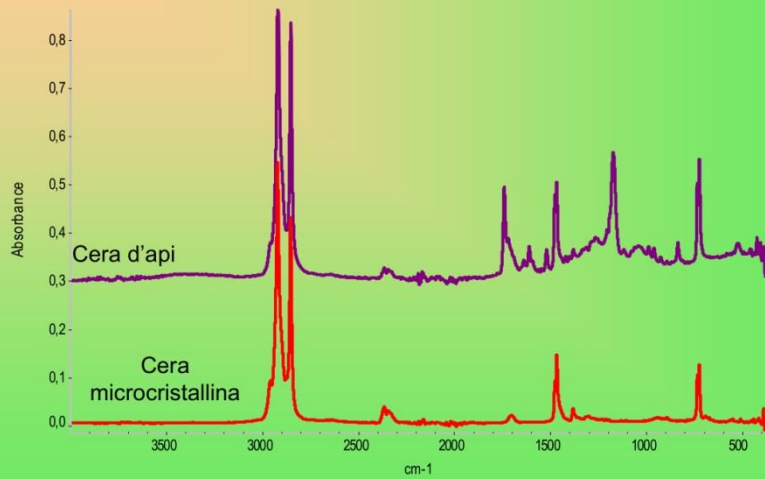
Resine naturali



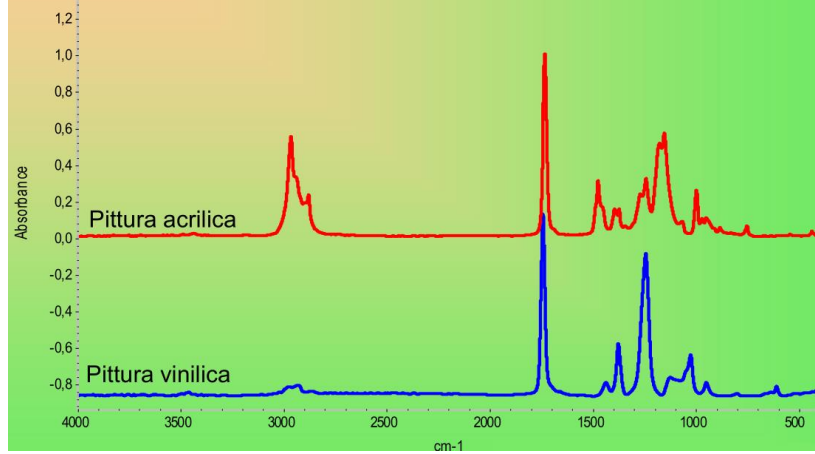
Olio di lino cotto



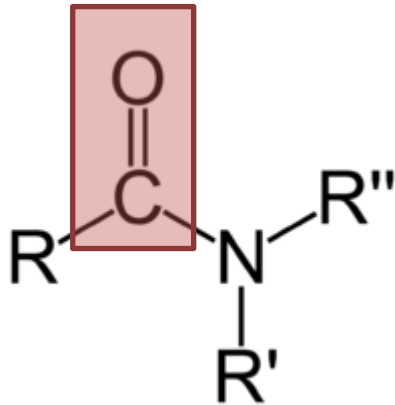
Cere



Resine sintetiche



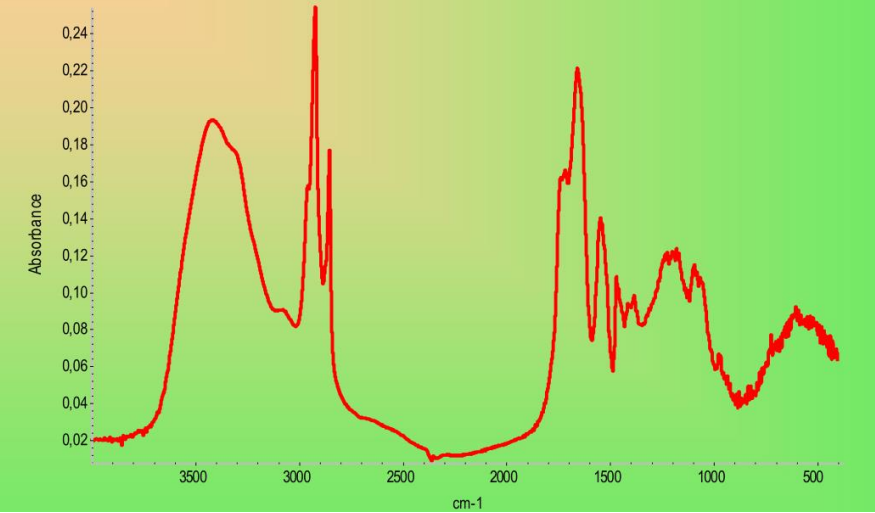
Le ammidi



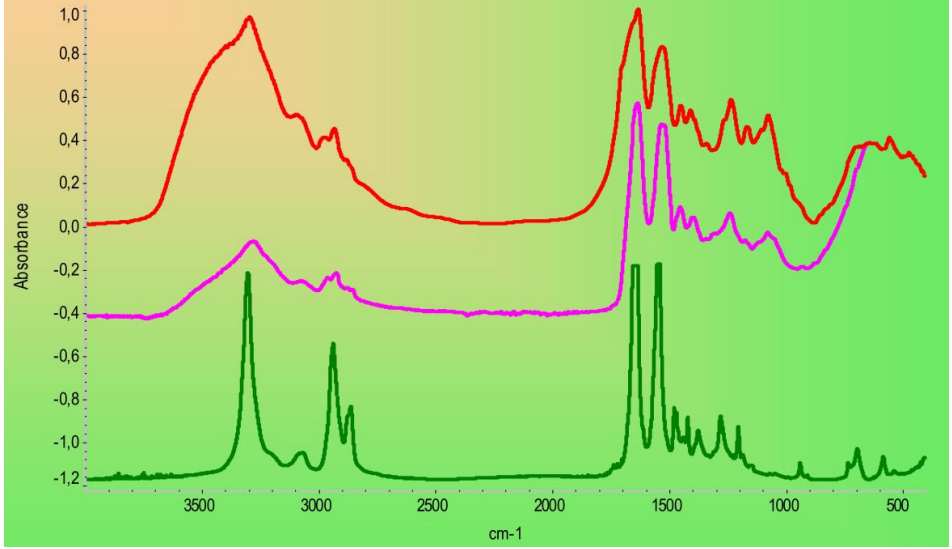
Struttura generale di un'amide. Se R' e R'' sono idrogeni l'amide si dice primaria, se solo uno fra R' ed R'' è un H, si dice secondaria, se R' ed R'' non sono idrogeni, l'amide si dice terziaria

Tempere all'uovo
Tempera grassa
Lana e seta
Colle animali
Cuoio e pelle
Caseina
Plastica

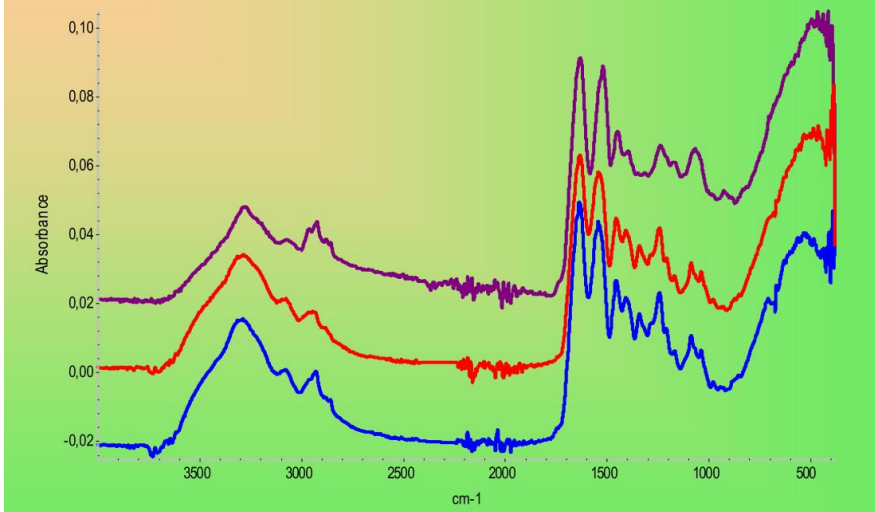
Tempere all'uovo



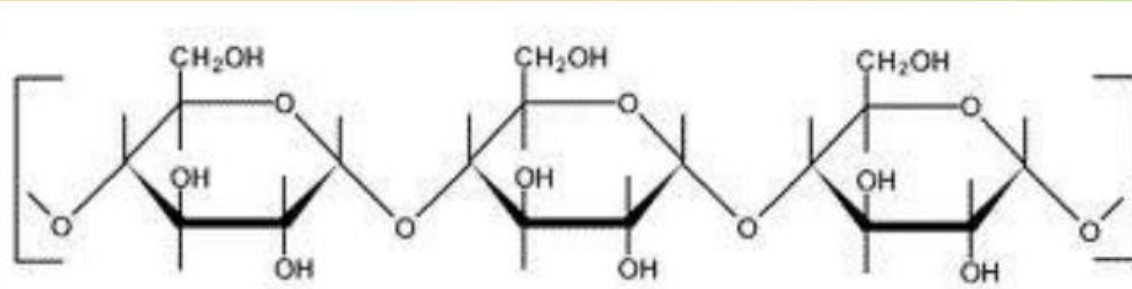
Lana, seta e nylon



Colla, caseina e cuoio

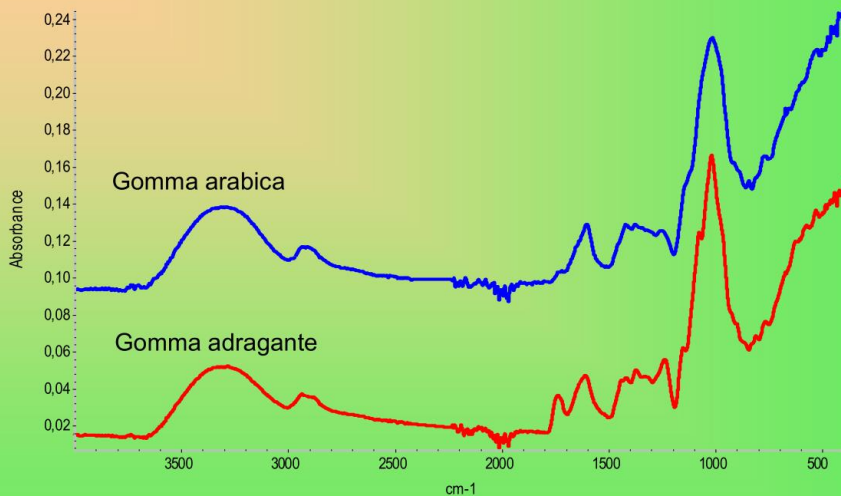


I polisaccaridi

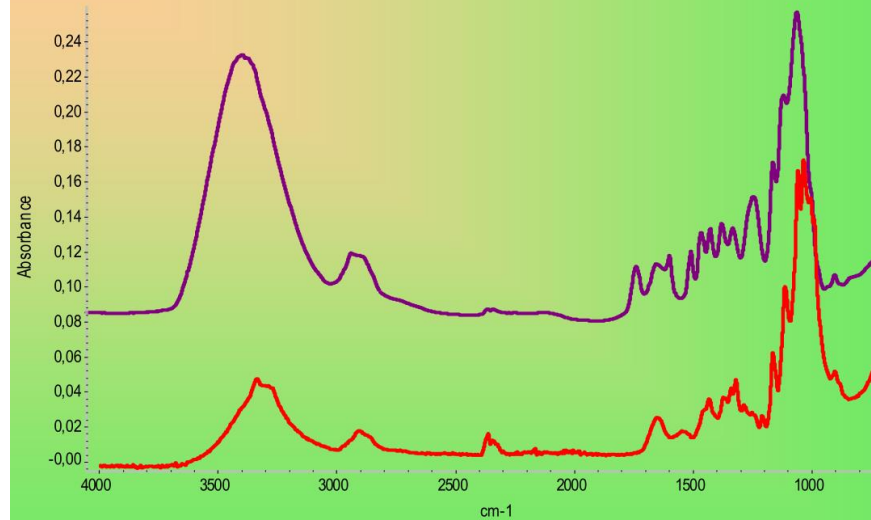


Acquerello
Gomme naturali
Legno
Carta
Fibre vegetali

Acquerello

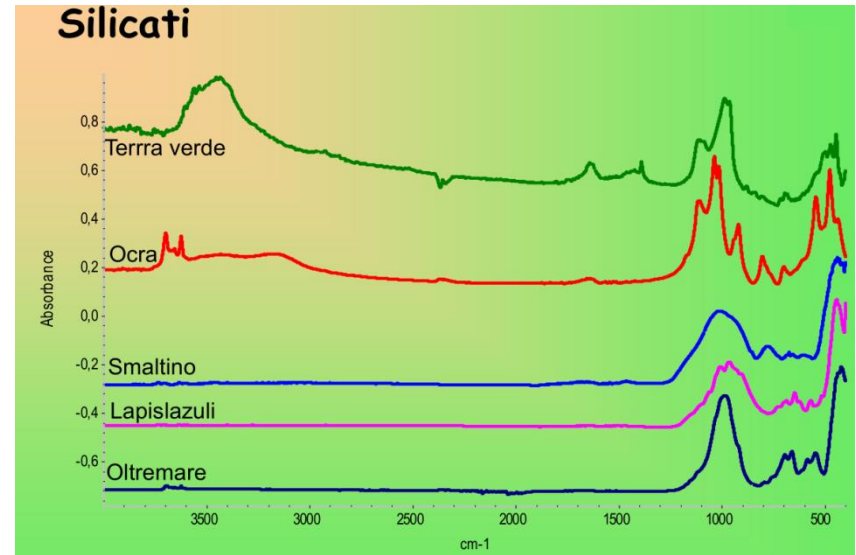
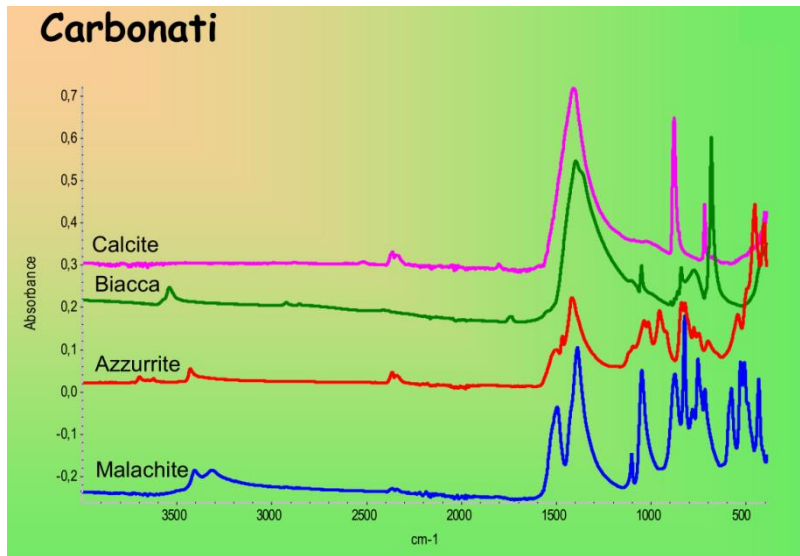


Legno e carta



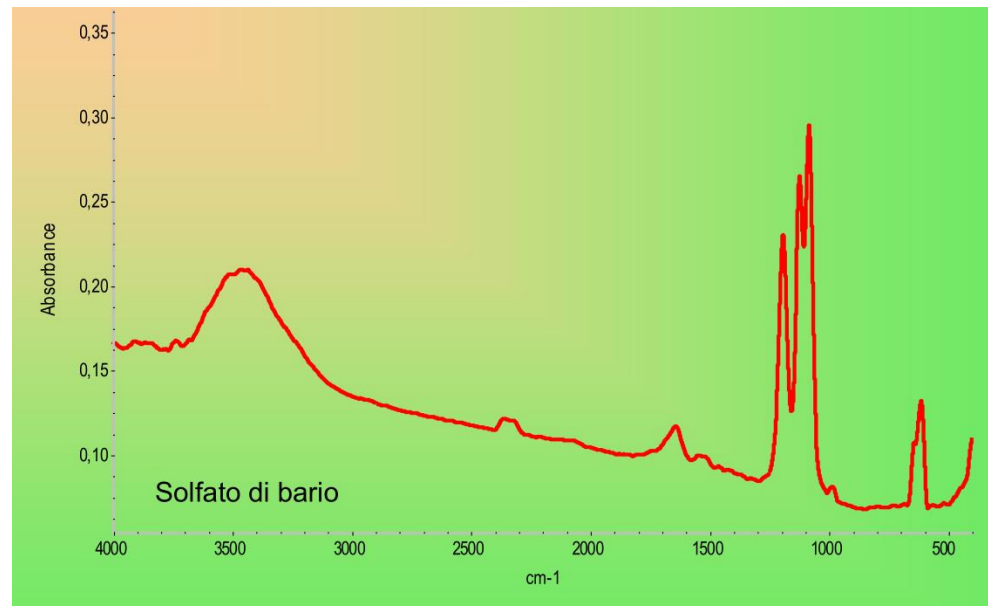
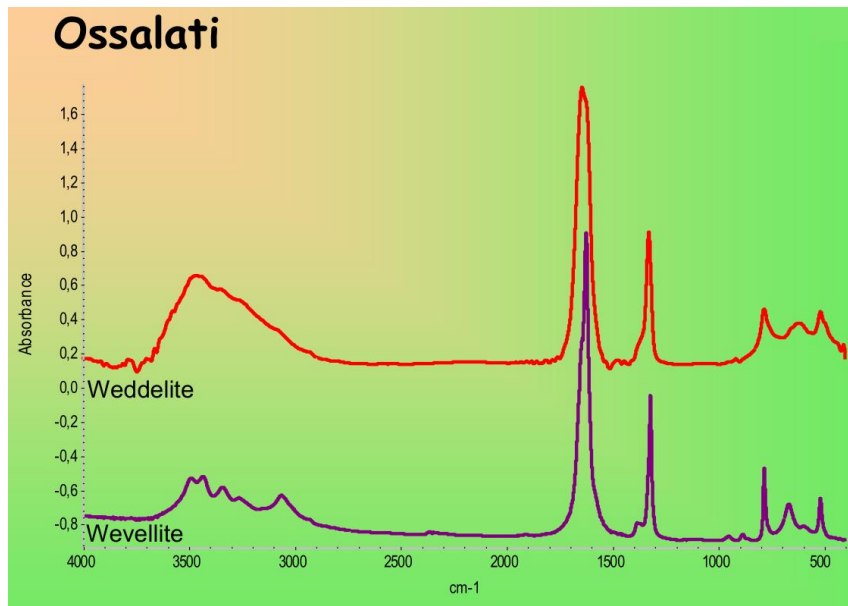
I pigmenti

- Carbonati
- Silicati
- Solfati
- Pigmenti organici



Prodotti di degrado comuni

- Solfati
- Ossalati
- Nitrati
- Saponi





DAFNE-LIGHT

INFN-LNF Synchrotron Radiation Facility

INFN

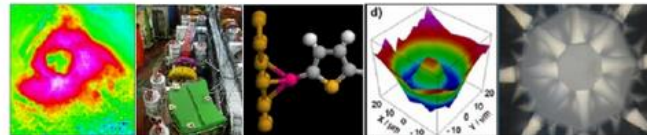
LNF

DAFNE Storage Ring

DAFNE-Light

Menu

- Home
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- General publications
- Highlights
- DAFNE storage ring parameters
- DAFNE status
- How to apply



DAFNE-Light

DAFNE-Light is the Synchrotron Radiation Facility at the Laboratori Nazionali di Frascati (LNF).

Three beamlines are operational using, in parasitic and dedicated mode, the intense photon emission of DAFNE, a 0.51 GeV storage ring with a routinely circulating electron current higher than 1 Ampere. Two of these beamlines (DXR1 and DXR2) have one of the DAFNE wiggler magnets as synchrotron radiation source, while the third beamline (SINBAD-IR) collects the radiation from a bending magnet. New XUV bending magnet beamlines are nowadays under construction.

The beamlines DXR1 and SINBAD-IR are open to [external users](#).

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cestelli@Inf.infn.it